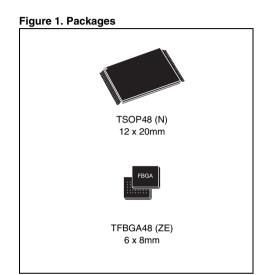


# M29DW323DT M29DW323DB

32 Mbit (4Mb x8 or 2Mb x16, Dual Bank 8:24, Boot Block) 3V Supply Flash Memory

# FEATURES SUMMARY

- SUPPLY VOLTAGE
  - V<sub>CC</sub> = 2.7V to 3.6V for Program, Erase and Read
  - V<sub>PP</sub> =12V for Fast Program (optional)
- ACCESS TIME: 70ns
- PROGRAMMING TIME
  - 10µs per Byte/Word typical
  - Double Word/ Quadruple Byte Program
- MEMORY BLOCKS
  - Dual Bank Memory Array: 8Mbit+24Mbit
  - Parameter Blocks (Top or Bottom Location)
- DUAL OPERATIONS
  - Read in one bank while Program or Erase in other
- ERASE SUSPEND and RESUME MODES
  - Read and Program another Block during Erase Suspend
- UNLOCK BYPASS PROGRAM COMMAND
   Faster Production/Batch Programming
- V<sub>PP</sub>/WP PIN for FAST PROGRAM and WRITE PROTECT
- TEMPORARY BLOCK UNPROTECTION MODE
- COMMON FLASH INTERFACE
  - 64 bit Security Code
- EXTENDED MEMORY BLOCK
  - Extra block used as security block or to store additional information
- LOW POWER CONSUMPTION
  - Standby and Automatic Standby
- 100,000 PROGRAM/ERASE CYCLES per BLOCK
- ELECTRONIC SIGNATURE
  - Manufacturer Code: 0020h
  - Top Device Code M29DW323DT: 225Eh
  - Bottom Device Code M29DW323DB: 225Fh



# TABLE OF CONTENTS

FEATURES SUMMARY 1
Figure 1. Packages1
TABLE OF CONTENTS
SUMMARY DESCRIPTION
Figure 2. Logic Diagram
Table 1. Signal Names    6
Figure 3. TSOP Connections
Figure 4. TFBGA48 Connections (Top view through package)
Table 2. Bank Architecture   8
Figure 5. Block Addresses (x8).
Figure 6. Block Addresses (x16) 10
SIGNAL DESCRIPTIONS
Address Inputs (A0-A20)
Data Inputs/Outputs (DQ0-DQ7)
Data Inputs/Outputs (DQ8-DQ14) 11
Data Input/Output or Address Input (DQ15A-1)11
Chip Enable (Ē)
Output Enable (G)
Write Enable (W)
V <sub>PP</sub> /Write Protect (V <sub>PP</sub> /WP)
Reset/Block Temporary Unprotect (RP)
Ready/Busy Output (RB)
Byte/Word Organization Select (BYTE)
V <sub>CC</sub> Supply Voltage (2.7V to 3.6V)
V <sub>SS</sub> Ground
BUS OPERATIONS
Bus Read
Bus Write
Output Disable
Standby
Automatic Standby
Special Bus Operations13
Electronic Signature
Block Protect and Chip Unprotect
Table 3. Bus Operations, $\overline{\text{BYTE}} = V_{\text{IL}}$
Table 4. Bus Operations, BYTE = VIH.    14
COMMAND INTERFACE
Read/Reset Command15
Auto Select Command15

	Read CFI Query Command	15
	Program Command	15
	Fast Program Commands	
	Quadruple Byte Program Command.	
	Double Word Program Command.	
	Unlock Bypass Command	
	Unlock Bypass Program Command	
	Unlock Bypass Reset Command	
	Chip Erase Command	
	Block Erase Command	
	Erase Suspend Command	
	Erase Resume Command	
	Enter Extended Block Command	
	Exit Extended Block Command	
	Block Protect and Chip Unprotect Commands	
	Table 5. Commands, 16-bit mode, <u>BYTE</u> = V <sub>IH</sub>	
	Table 6. Commands, 8-bit mode, BYTE = VIL.	
	Table 7.         Program, Erase Times and Program, Erase Endurance Cycles	19
ст	ATUS REGISTER	20
31/		
	Data Polling Bit (DQ7).	
	Toggle Bit (DQ6)	
	Error Bit (DQ5)	
	Erase Timer Bit (DQ3).	
	Alternative Toggle Bit (DQ2)	
	Table 8.     Status Register Bits	
	Figure 7. Data Polling Flowchart.	
	Figure 8. Toggle Flowchart	21
DU	AL OPERATIONS AND MULTIPLE BANK ARCHITECTURE	22
	Table 9. Dual Operations Allowed In the Other Bank	22
	Table 10. Dual Operations Allowed In Same Bank	
MA	XIMUM RATING	23
	Table 11. Absolute Maximum Ratings	23
DC	and AC PARAMETERS	24
-	Table 12. Operating and AC Measurement Conditions	
	Figure 9. AC Measurement I/O Waveform	
	Figure 9. AC Measurement Load Circuit	
	Table 13. Device Capacitance.	
	Table 13. Device Capacitance.	
	Figure 11.Read Mode AC Waveforms.	
	Table 15. Read AC Characteristics	
	Figure 12. Write AC Waveforms, Write Enable Controlled	
	Table 16. Write AC Characteristics, Write Enable Controlled	
		~1

Figure 13.Write AC Waveforms, Chip Enable Controlled28Table 17. Write AC Characteristics, Chip Enable Controlled.28Figure 14.Toggle and Alternative Toggle Bits Mechanism, Chip Enable Controlled.29Figure 15.Toggle and Alternative Toggle Bits Mechanism, Output Enable Controlled29Table 18. Toggle and Alternative Toggle Bits AC Characteristics.29Figure 16.Reset/Block Temporary Unprotect AC Waveforms30Table 19. Reset/Block Temporary Unprotect AC Characteristics30Figure 17.Accelerated Program Timing Waveforms30
PACKAGE MECHANICAL
Figure 18.TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Bottom View Package Outline 31 Table 20. TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Package Mechanical Data 31 Figure 19.TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Bottom View Package Outline 32 Table 21. TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Package Mechanical Data 32
PART NUMBERING
Table 22. Ordering Information Scheme    33
APPENDIX A.BLOCK ADDRESSES
Table 23. Top Boot Block Addresses, M29DW323DT.       34         Table 24. Bottom Boot Block Addresses, M29DW323DB.       37
APPENDIX B.COMMON FLASH INTERFACE (CFI)
Table 25. Query Structure Overview40Table 26. CFI Query Identification String.40Table 27. CFI Query System Interface Information41Table 28. Device Geometry Definition41Table 29. Primary Algorithm-Specific Extended Query Table42Table 30. Security Code Area42
APPENDIX C.EXTENDED MEMORY BLOCK
Factory Locked Extended Block       43         Customer Lockable Extended Block       43         Table 31. Extended Block Address and Data       43
APPENDIX D.BLOCK PROTECTION
Programmer Technique       44         In-System Technique       44         Table 32. Programmer Technique Bus Operations, BYTE = VIH or VIL       44         Figure 20.Programmer Equipment Group Protect Flowchart       45         Figure 21.Programmer Equipment Chip Unprotect Flowchart       46         Figure 22.In-System Equipment Group Protect Flowchart       47         Figure 23.In-System Equipment Chip Unprotect Flowchart       48
REVISION HISTORY

Table 33. Document Revision History		49
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# SUMMARY DESCRIPTION

The M29DW323D is a 32 Mbit (4Mb x8 or 2Mb x16) non-volatile memory that can be read, erased and reprogrammed. These operations can be performed using a single low voltage (2.7 to 3.6V) supply. On power-up the memory defaults to its Read mode.

The device features an asymmetrical block architecture. The M29DW323D has an array of 8 parameter and 63 main blocks and is divided into two Banks, A and B, providing Dual Bank operations. While programming or erasing in Bank A, read operations are possible in Bank B and vice versa. Only one bank at a time is allowed to be in program or erase mode. The bank architecture is summarized in Table 2. M29DW323DT locates the Parameter Blocks at the top of the memory address space while the M29DW323DB locates the Parameter Blocks starting from the bottom.

M29DW323D has an extra 32 KWord (x16 mode) or 64 KByte (x8 mode) block, the Extended Block, that can be accessed using a dedicated command. The Extended Block can be protected and so is useful for storing security information. How-

#### V<sub>CC</sub> V<sub>PP</sub>/ $\overline{WP}$ 40-A20 $\overline{W}$ $\overline{W}$

#### Figure 2. Logic Diagram

ever the protection is irreversible, once protected the protection cannot be undone.

Each block can be erased independently so it is possible to preserve valid data while old data is erased. The blocks can be protected to prevent accidental Program or Erase commands from modifying the memory. Program and Erase commands are written to the Command Interface of the memory. An on-chip Program/Erase Controller simplifies the process of programming or erasing the memory by taking care of all of the special operations that are required to update the memory contents. The end of a program or erase operation can be detected and any error conditions identified. The command set required to control the memory is consistent with JEDEC standards.

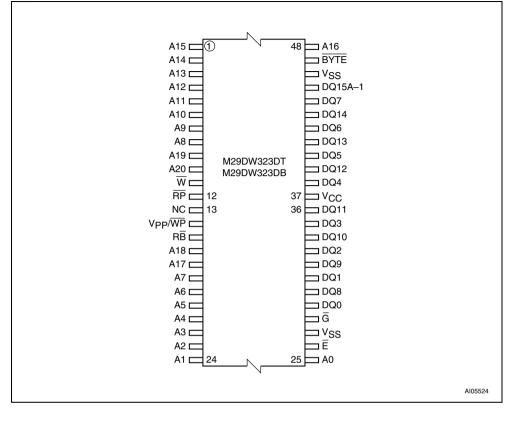
Chip Enable, Output Enable and Write Enable signals control the bus operation of the memory. They allow simple connection to most microprocessors, often without additional logic.

The memory is offered in TSOP48 (12x20mm), and TFBGA48 (6x8mm, 0.8mm pitch) packages. The memory is supplied with all the bits erased (set to '1').

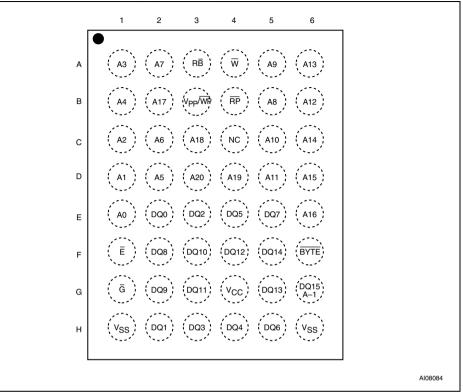
Address Inputs
Data Inputs/Outputs
Data Inputs/Outputs
Data Input/Output or Address Input
Chip Enable
Output Enable
Write Enable
Reset/Block Temporary Unprotect
Ready/Busy Output
Byte/Word Organization Select
Supply Voltage
V <sub>PP</sub> /Write Protect
Ground
Not Connected Internally

#### Table 1. Signal Names

#### Figure 3. TSOP Connections



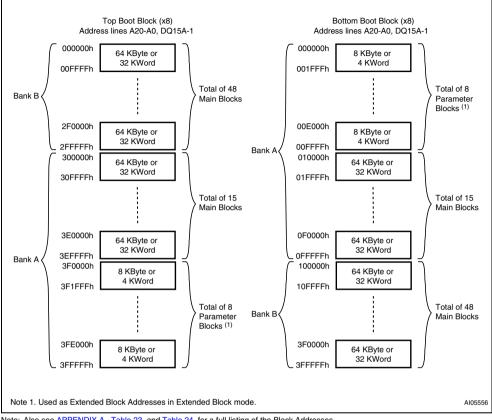
#### Figure 4. TFBGA48 Connections (Top view through package)



#### Table 2. Bank Architecture

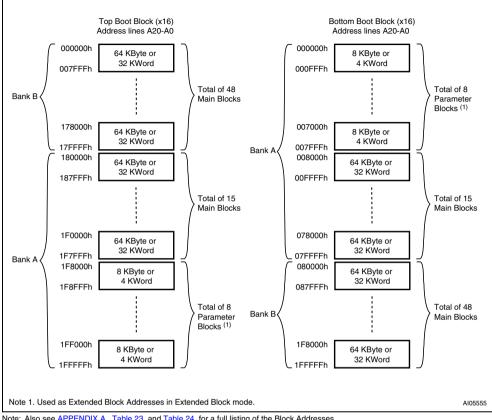
Bank	Bank Size	Param	eter Blocks	Maiı	n Blocks
Dalik	Dalik Size	No. of Blocks	Block Size	No. of Blocks	Block Size
A	8 Mbit	8	8KByte/ 4 KWord	15	64KByte/ 32 KWord
В	24 Mbit	-		48	64KByte/ 32 KWord

#### Figure 5. Block Addresses (x8)



Note: Also see APPENDIX A., Table 23. and Table 24. for a full listing of the Block Addresses.

### Figure 6. Block Addresses (x16)



Note: Also see APPENDIX A., Table 23. and Table 24. for a full listing of the Block Addresses.



# SIGNAL DESCRIPTIONS

See Figure 2., Logic Diagram, and Table 1., Signal Names, for a brief overview of the signals connected to this device.

Address Inputs (A0-A20). The Address Inputs select the cells in the memory array to access during Bus Read operations. During Bus Write operations they control the commands sent to the Command Interface of the Program/Erase Controller.

**Data Inputs/Outputs (DQ0-DQ7).** The Data I/O outputs the data stored at the selected address during a Bus Read operation. During Bus Write operations they represent the commands sent to the Command Interface of the Program/Erase Controller.

**Data Inputs/Outputs (DQ8-DQ14).** The Data I/O outputs the data stored at the selected address during a Bus Read operation when BYTE is High,  $V_{IH}$ . When BYTE is Low,  $V_{IL}$ , these pins are not used and are high impedance. During Bus Write operations the Command Register does not use these bits. When reading the Status Register these bits should be ignored.

Data Input/Output or Address Input (DQ15A-1).

When  $\overrightarrow{\text{BYTE}}$  is High, V<sub>IH</sub>, this pin behaves as a  $\overrightarrow{\text{Data}}$  Input/Output pin (as DQ8-DQ14). When  $\overrightarrow{\text{BYTE}}$  is Low, V<sub>IL</sub>, this pin behaves as an address pin; DQ15A–1 Low will select the LSB of the addressed Word, DQ15A–1 High will select the MSB. Throughout the text consider references to the Data Input/Output to include this pin when  $\overrightarrow{\text{BYTE}}$  is High and references to the Address Inputs to include this pin when  $\overrightarrow{\text{BYTE}}$  is Low except when stated explicitly otherwise.

**Chip Enable** ( $\overline{E}$ ). The Chip Enable,  $\overline{E}$ , activates the memory, allowing Bus Read and Bus Write operations to be performed. When Chip Enable is High, V<sub>IH</sub>, all other pins are ignored.

**Output Enable** ( $\overline{\mathbf{G}}$ ). The Output Enable,  $\overline{\mathbf{G}}$ , controls the Bus Read operation of the memory.

Write Enable ( $\overline{W}$ ). The Write Enable,  $\overline{W}$ , controls the Bus Write operation of the memory's Command Interface.

 $V_{PP}/Write$  Protect ( $V_{PP}/\overline{WP}$ ). The  $V_{PP}/Write$ Protect pin provides two functions. The  $V_{PP}$  function allows the memory to use an external high voltage power supply to reduce the time required for Program operations. This is achieved by bypassing the unlock cycles and/or using the Double Word or Quadruple Byte Program commands. The Write Protect function provides a hardware method of protecting the two outermost boot blocks.

When  $V_{PP}$ /Write Protect is Low,  $V_{IL}$ , the memory protects the two outermost boot blocks; Program

and Erase operations in these blocks are ignored while  $V_{PP}$ /Write Protect is Low, even when RP is at  $V_{ID}$ .

When  $V_{PP}$ /Write Protect is High,  $V_{IH}$ , the memory reverts to the previous protection status of the two outermost boot blocks. Program and Erase operations can now modify the data in these blocks unless the blocks are protected using Block Protection.

When V<sub>PP</sub>/Write Protect is raised to V<sub>PP</sub> the memory automatically enters the Unlock Bypass mode. When V<sub>PP</sub>/Write Protect returns to V<sub>IH</sub> or V<sub>IL</sub> normal operation resumes. During Unlock Bypass Program operations the memory draws I<sub>PP</sub> from the pin to supply the programming circuits. See the description of the Unlock Bypass command in the Command Interface section. The transitions from V<sub>IH</sub> to V<sub>PP</sub> and from V<sub>PP</sub> to V<sub>IH</sub> must be slower than t<sub>VHVPP</sub>, see Figure 17.

Never raise V<sub>PP</sub>/Write Protect to V<sub>PP</sub> from any mode except Read mode, otherwise the memory may be left in an indeterminate state.

The V<sub>PP</sub>/Write Protect pin must not be left floating or unconnected or the device may become unreliable. A  $0.1\mu$ F capacitor should be connected between the V<sub>PP</sub>/Write Protect pin and the V<sub>SS</sub> Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Unlock Bypass Program, I<sub>PP</sub>.

**Reset/Block Temporary Unprotect (RP).** The Reset/Block Temporary Unprotect pin can be used to apply a Hardware Reset to the memory or to temporarily unprotect all Blocks that have been protected.

Note that if  $V_{PP}/\overline{WP}$  is at  $V_{IL}$ , then the two outermost boot blocks will remain protected even if RP is at  $V_{ID}$ .

A Hardware Reset is achieved by holding Reset/ Block Temporary Unprotect Low, V<sub>IL</sub>, for at least  $t_{PLPX}$ . After Reset/Block Temporary Unprotect goes High, V<sub>IH</sub>, the memory will be ready for Bus Read and Bus Write operations after  $t_{PHEL}$  or  $t_{RHEL}$ , whichever occurs last. See the Ready/Busy Output section, Table 19. and Figure 16., Reset/ Block Temporary Unprotect AC Waveforms, for more details.

Holding  $\overline{\text{RP}}$  at V<sub>ID</sub> will temporarily unprotect the protected Blocks in the memory. Program and Erase operations on all blocks will be possible. The transition from V<sub>IH</sub> to V<sub>ID</sub> must be slower than t<sub>PHPHH</sub>.

**Ready/Busy Output (RB).** The Ready/Busy pin is an open-drain output that can be used to identify when the device is performing a Program or Erase operation. During Program or Erase operations Ready/Busy is Low,  $V_{OL}$ . Ready/Busy is high-impedance during Read mode, Auto Select mode and Erase Suspend mode.

After a Hardware Reset, Bus Read and Bus Write operations cannot begin until Ready/Busy becomes high-impedance. See Table 19. and Figure 16., Reset/Block Temporary Unprotect AC Waveforms.

The use of an open-drain output allows the Ready/ Busy pins from several memories to be connected to a single pull-up resistor. A Low will then indicate that one, or more, of the memories is busy.

Byte/Word Organization Select (BYTE). The Byte/Word Organization Select pin is used to switch between the x8 and x16 Bus modes of the memory. When Byte/Word Organization Select is Low,  $V_{L}$ , the memory is in x8 mode, when it is High,  $V_{IH}$ , the memory is in x16 mode.  $V_{CC}$  Supply Voltage (2.7V to 3.6V).  $V_{CC}$  provides the power supply for all operations (Read, Program and Erase).

The Command Interface is disabled when the V<sub>CC</sub> Supply Voltage is less than the Lockout Voltage, V<sub>LKO</sub>. This prevents Bus Write operations from accidentally damaging the data during power up, power down and power surges. If the Program/ Erase Controller is programming or erasing during this time then the operation aborts and the memory contents being altered will be invalid.

A 0.1 $\mu$ F capacitor should be connected between the V<sub>CC</sub> Supply Voltage pin and the V<sub>SS</sub> Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Program and Erase operations, I<sub>CC3</sub>.

 $V_{SS}\,Ground.\,\,V_{SS}$  is the reference for all voltage measurements. The device features two  $V_{SS}\,$  pins which must be both connected to the system ground.



# **BUS OPERATIONS**

There are five standard bus operations that control the device. These are Bus Read, Bus Write, Output Disable, Standby and Automatic Standby.

The Dual Bank architecture of the M29DW323 allows read/write operations in Bank A, while read operations are being executed in Bank B or vice versa. Write operations are only allowed in one bank at a time.

See Tables 3 and 4, Bus Operations, for a summary. Typically glitches of less than 5ns on Chip Enable or Write Enable are ignored by the memory and do not affect bus operations.

**Bus Read.** Bus Read operations read from the memory cells, or specific registers in the Command Interface. A valid Bus Read operation involves setting the desired address on the Address Inputs, applying a Low signal,  $V_{IL}$ , to Chip Enable and Output Enable and keeping Write Enable High,  $V_{IH}$ . The Data Inputs/Outputs will output the value, see Figure 11., Read Mode AC Waveforms, and Table 15., Read AC Characteristics, for details of when the output becomes valid.

**Bus Write.** Bus Write operations write to the Command Interface. A valid Bus Write operation begins by setting the desired address on the Address Inputs. The Address Inputs are latched by the Command Interface on the falling edge of Chip Enable or Write Enable, whichever occurs last. The Data Inputs/Outputs are latched by the Command Interface on the rising edge of Chip Enable or Write Enable, whichever occurs first. Output Enable must remain High, V<sub>IH</sub>, during the whole Bus Write operation. See Figures 12 and 13, Write AC Waveforms, and Tables 16 and 17, Write AC Characteristics, for details of the timing requirements.

**Output Disable.** The Data Inputs/Outputs are in the high impedance state when Output Enable is High,  $V_{\text{IH}}$ .

**Standby.** When Chip Enable is High,  $V_{IH}$ , the memory enters Standby mode and the Data Inputs/Outputs pins are placed in the high-imped-

ance state. To reduce the Supply Current to the Standby Supply Current,  $I_{CC2}$ , Chip Enable should be held within  $V_{CC} \pm 0.2V$ . For the Standby current level see Table 14., DC Characteristics.

During program or erase operations the memory will continue to use the Program/Erase Supply Current,  $I_{CC3}$ , for Program or Erase operations until the operation completes.

Automatic Standby. If CMOS levels ( $V_{CC} \pm 0.2V$ ) are used to drive the bus and the bus is inactive for 300ns or more the memory enters Automatic Standby where the internal Supply Current is reduced to the Standby Supply Current,  $I_{CC2}$ . The Data Inputs/Outputs will still output data if a Bus Read operation is in progress.

#### **Special Bus Operations**

Additional bus operations can be performed to read the Electronic Signature and also to apply and remove Block Protection. These bus operations are intended for use by programming equipment and are not usually used in applications. They require  $V_{\rm ID}$  to be applied to some pins.

**Electronic Signature.** The memory has two codes, the manufacturer code and the device code, that can be read to identify the memory. These codes can be read by applying the signals listed in Tables 3 and 4, Bus Operations.

Block Protect and Chip Unprotect. Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in APPENDIX A., Tables 23 and 24, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed.

The V<sub>PP</sub>/Write Protect pin can be used to protect the two outermost boot blocks. When V<sub>PP</sub>/Write Protect is at V<sub>IL</sub> the two outermost boot blocks are protected and remain protected regardless of the Block Protection Status or the Reset/Block Temporary Unprotect pin status.

Block Protect and Chip Unprotect operations are described in APPENDIX D.

Onevetien	Ē	G	W Address Inputs		Data	a Inputs/Outputs
Operation	-	G	vv	DQ15A-1, A0-A20	DQ14-DQ8         DQ7-DQ0           Hi-Z         Data Output           Hi-Z         Data Input	
Bus Read	VIL	VIL	VIH	Cell Address	Hi-Z	Data Output
Bus Write	VIL	VIH	V <sub>IL</sub>	Command Address	Hi-Z	Data Input
Output Disable	Х	VIH	VIH	х	Hi-Z	Hi-Z
Standby	VIH	Х	Х	х	Hi-Z	Hi-Z
Read Manufacturer Code	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IL},  A1 = V_{IL},  A9 = V_{ID}, \\ Others  V_{IL}  or  V_{IH} \end{array}$	Hi-Z	20h
Read Device Code	VIL	V <sub>IL</sub>	V <sub>IH</sub>		Hi-Z	5Eh (M29DW323DT) 5Fh (M29DW323DB)
Extended Memory Block Verify Code	VIL	VIL	V <sub>IH</sub>		Hi-Z	81h (factory locked) 01h (not factory locked)

# Table 3. Bus Operations, $\overline{\text{BYTE}} = V_{\text{IL}}$

Note:  $X = V_{IL}$  or  $V_{IH}$ .

# Table 4. Bus Operations, $\overline{\text{BYTE}} = V_{\text{IH}}$

Operation	Ē	G	w	Address Inputs A0-A20	Data Inputs/Outputs DQ15A-1, DQ14-DQ0
Bus Read	VIL	VIL	VIH	Cell Address	Data Output
Bus Write	VIL	VIH	VIL	Command Address	Data Input
Output Disable	х	VIH	VIH	Х	Hi-Z
Standby	VIH	х	Х	Х	Hi-Z
Read Manufacturer Code	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IL},  A1 = V_{IL},  A9 = V_{ID}, \\ Others  V_{IL}  or  V_{IH} \end{array}$	0020h
Read Device Code	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IH}, \ A1 = V_{IL}, \ A9 = V_{ID}, \\ Others \ V_{IL} \ or \ V_{IH} \end{array}$	225Eh (M29DW323DT) 225Fh (M29DW323DB)
Extended Memory Block Verify Code	V <sub>IL</sub>	V <sub>IL</sub>	VIH	$      A0 = V_{IH}, A1 = V_{IH}, A6 = V_{IL}, \\       A9 = V_{ID}, Others V_{IL} \text{ or } V_{IH} $	81h (factory locked) 01h (not factory locked)

Note: X = V<sub>IL</sub> or V<sub>IH</sub>.



# COMMAND INTERFACE

All Bus Write operations to the memory are interpreted by the Command Interface. Commands consist of one or more sequential Bus Write operations. Failure to observe a valid sequence of Bus Write operations will result in the memory returning to Read mode. The long command sequences are imposed to maximize data security.

The address used for the commands changes depending on whether the memory is in 16-bit or 8bit mode. See either Table 5, or 6, depending on the configuration that is being used, for a summary of the commands.

#### **Read/Reset Command**

The Read/Reset command returns the memory to its Read mode. It also resets the errors in the Status Register. Either one or three Bus Write operations can be used to issue the Read/Reset command.

The Read/Reset command can be issued, between Bus Write cycles before the start of a program or erase operation, to return the device to read mode. If the Read/Reset command is issued during the time-out of a Block erase operation then the memory will take up to 10µs to abort. During the abort period no valid data can be read from the memory. The Read/Reset command will not abort an Erase operation when issued while in Erase Suspend.

#### Auto Select Command

The Auto Select command is used to read the Manufacturer Code, the Device Code, the Block Protection Status and the Extended Memory Block Verify Code. It can be addressed to either Bank. Three consecutive Bus Write operations are required to issue the Auto Select command. The final Write cycle must be addressed to one of the Banks. Once the Auto Select command is issued Bus Read operations to the Bank where the command was issued output the Auto Select data. Bus Read operations to the other Bank will output the contents of the memory array. The memory remains in Auto Select mode until a Read/Reset or CFI Query command is issued.

In Auto Select mode the Manufacturer Code can be read using a Bus Read operation with  $A0 = V_{IL}$  and  $A1 = V_{IL}$  and A19-A20 = Bank Address. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ .

The Device Code can be read using a Bus Read operation with A0 =  $V_{IH}$  and A1 =  $V_{IL}$  and A19-A20 = Bank Address. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ .

The Block Protection Status of each block can be read using a Bus Read operation with A0 =  $V_{IL}$ , A1 =  $V_{IH}$ , A19-A20 = Bank Address and A12-A18 specifying the address of the block inside the

Bank. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ . If the addressed block is protected then 01h is output on Data Inputs/Outputs DQ0-DQ7, otherwise 00h is output.

#### **Read CFI Query Command**

The Read CFI Query Command is used to read data from the Common Flash Interface (CFI) Memory Area. This command is valid when the device is in the Read Array mode, or when the device is in Auto Select mode.

One Bus Write cycle is required to issue the Read CFI Query Command. Once the command is issued subsequent Bus Read operations read from the Common Flash Interface Memory Area.

The Read/Reset command must be issued to return the device to the previous mode (the Read Array mode or Auto Select mode). A second Read/ Reset command would be needed if the device is to be put in the Read Array mode from Auto Select mode.

See APPENDIX B., Tables 25, 26, 27, 28, 29 and 30 for details on the information contained in the Common Flash Interface (CFI) memory area.

#### **Program Command**

The Program command can be used to program a value to one address in the memory array at a time. The command requires four Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

If the address falls in a protected block then the Program command is ignored, the data remains unchanged. The Status Register is never read and no error condition is given.

During the program operation the memory will ignore all commands. It is not possible to issue any command to abort or pause the operation. After programming has started, Bus Read operations in the Bank being programmed output the Status Register content, while Bus Read operations to the other Bank output the contents of the memory array. See the section on the Status Register for more details. Typical program times are given in Table 7.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Program command cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

#### Fast Program Commands

There are two Fast Program commands available to improve the programming throughput, by writing several adjacent words or bytes in parallel. The Quadruple Byte Program command is available for x8 operations, while the Double Word Program command is available for x16 operations.

Only one bank can be programmed at any one time. The other bank must be in Read mode or Erase Suspend.

Fast Program commands should not be attempted when  $V_{PP}/WP$  is not at  $V_{PP}$ . Care must be taken because applying a 12V  $V_{PP}$  voltage to the VPP/ WP pin will temporarily unprotect any protected block.

After programming has started, Bus Read operations in the Bank being programmed output the Status Register content, while Bus Read operations to the other Bank output the contents of the memory array.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Fast Program commands cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Typical Program times are given in Table 7., Program, Erase Times and Program, Erase Endurance Cycles.

**Quadruple Byte Program Command.** The Quadruple Byte Program command is used to write a page of four adjacent Bytes in parallel. The four bytes must differ only for addresses A0, DQ15A-1. Five bus write cycles are necessary to issue the Quadruple Byte Program command.

- The first bus cycle sets up the Quadruple Byte Program Command.
- The second bus cycle latches the Address and the Data of the first byte to be written.
- The third bus cycle latches the Address and the Data of the second byte to be written.
- The fourth bus cycle latches the Address and the Data of the third byte to be written.
- The fifth bus cycle latches the Address and the Data of the fourth byte to be written and starts the Program/Erase Controller.

**Double Word Program Command.** The Double Word Program command is used to write a page of two adjacent words in parallel. The two words must differ only for the address A0.

Three bus write cycles are necessary to issue the Double Word Program command.

- The first bus cycle sets up the Double Word Program Command.
- The second bus cycle latches the Address and the Data of the first word to be written.
- The third bus cycle latches the Address and the Data of the second word to be written and starts the Program/Erase Controller.

#### **Unlock Bypass Command**

The Unlock Bypass command is used in conjunction with the Unlock Bypass Program command to program the memory faster than with the standard program commands. When the cycle time to the device is long, considerable time saving can be made by using these commands. Three Bus Write operations are required to issue the Unlock Bypass command.

Once the Unlock Bypass command has been issued the bank enters Unlock Bypass mode. When in Unlock Bypass mode, only the Unlock Bypass Program and Unlock Bypass Reset commands are valid. The Unlock Bypass Program command can be issued to program addresses within the bank, and the Unlock Bypass Reset command to return the bank to Read mode. In Unlock Bypass mode the memory can be read as if in Read mode.

When  $V_{PP}$  is applied to the  $V_{PP}$ /Write Protect pin the memory automatically enters the Unlock Bypass mode and the Unlock Bypass Program command can be issued immediately. Care must be taken because applying a 12V  $V_{PP}$  voltage to the VPP/WP pin will temporarily unprotect any protected block.

#### **Unlock Bypass Program Command**

The Unlock Bypass Program command can be used to program one address in the memory array at a time. The command requires two Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

The Program operation using the Unlock Bypass Program command behaves identically to the Program operation using the Program command. The operation cannot be aborted, a Bus Read operation to the Bank where the command was issued outputs the Status Register. See the Program command for details on the behavior.

#### Unlock Bypass Reset Command

The Unlock Bypass Reset command can be used to return to Read/Reset mode from Unlock Bypass Mode. Two Bus Write operations are required to issue the Unlock Bypass Reset command. Read/ Reset command does not exit from Unlock Bypass Mode.



#### Chip Erase Command

The Chip Erase command can be used to erase the entire chip. Six Bus Write operations are required to issue the Chip Erase Command and start the Program/Erase Controller.

If any blocks are protected then these are ignored and all the other blocks are erased. If all of the blocks are protected the Chip Erase operation appears to start but will terminate within about  $100\mu$ s, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the erase operation the memory will ignore all commands, including the Erase Suspend command. It is not possible to issue any command to abort the operation. Typical chip erase times are given in Table 7. All Bus Read operations during the Chip Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Chip Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read Mode.

The Chip Erase Command sets all of the bits in unprotected blocks of the memory to '1'. All previous data is lost.

#### **Block Erase Command**

The Block Erase command can be used to erase a list of one or more blocks in a Bank. It sets all of the bits in the unprotected selected blocks to '1'. All previous data in the selected blocks is lost.

Six Bus Write operations are required to select the first block in the list. Each additional block in the list can be selected by repeating the sixth Bus Write operation using the address of the additional block. All blocks must belong to the same Bank: if a block belonging to the other Bank is given it will not be erased. The Block Erase operation starts the Program/Erase Controller after a time-out period of 50µs after the last Bus Write operation. Once the Program/Erase Controller starts it is not possible to select any more blocks. Each additional block must therefore be selected within 50us of the last block. The 50µs timer restarts when an additional block is selected. After the sixth Bus Write operation a Bus Read operation within the same Bank will output the Status Register. See the Status Register section for details on how to identify if the Program/Erase Controller has started the Block Erase operation.

If any selected blocks are protected then these are ignored and all the other selected blocks are erased. If all of the selected blocks are protected the Block Erase operation appears to start but will terminate within about 100µs, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the Block Erase operation the memory will ignore all commands except the Erase Suspend command and the Read/Reset command which is only accepted during the 50µs time-out period. Typical block erase times are given in Table 7.

After the Erase operation has started all Bus Read operations to the Bank being erased will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Block Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

#### **Erase Suspend Command**

The Erase Suspend Command may be used to temporarily suspend a Block Erase operation and return the memory to Read mode. The command requires one Bus Write operation.

The Program/Erase Controller will suspend within the Erase Suspend Latency time of the Erase Suspend Command being issued. Once the Program/ Erase Controller has stopped the memory will be set to Read mode and the Erase will be suspended. If the Erase Suspend command is issued during the period when the memory is waiting for an additional block (before the Program/Erase Controller starts) then the Erase is suspended immediately and will start immediately when the Erase Resume Command is issued. It is not possible to select any further blocks to erase after the Erase Resume.

During Erase Suspend it is possible to Read and Program cells in blocks that are not being erased; both Read and Program operations behave as normal on these blocks. If any attempt is made to program in a protected block or in the suspended block then the Program command is ignored and the data remains unchanged. The Status Register is not read and no error condition is given. Reading from blocks that are being erased will output the Status Register.

It is also possible to issue the Auto Select, Read CFI Query and Unlock Bypass commands during an Erase Suspend. The Read/Reset command must be issued to return the device to Read Array mode before the Resume command will be accepted.

During Erase Suspend a Bus Read operation to the Extended Block will output the Extended Block data.

#### **Erase Resume Command**

The Erase Resume command must be used to restart the Program/Erase Controller after an Erase Suspend. The device must be in Read Array mode before the Resume command will be accepted. An erase can be suspended and resumed more than once.

#### Enter Extended Block Command

The M29DW323D has an extra 64KByte block (Extended Block) that can only be accessed using the Enter Extended Block command. Three Bus write cycles are required to issue the Extended Block command. Once the command has been issued the device enters Extended Block mode where all Bus Read or Program operations to the Boot Block addresses access the Extended Block. The Extended Block (with the same address as the boot block) cannot be erased, and can be treated as one-time programmable (OTP) memory. In Extended Block mode the Boot Blocks are not accessible. In Extended Block mode dual operations are possible, with the Extended Block mapped in Bank A. When in Extended Block mode, Erase Commands in Bank A are not allowed.

To exit from the Extended Block mode the Exit Extended Block command must be issued.

The Extended Block can be protected, however once protected the protection cannot be undone.

#### Exit Extended Block Command

The Exit Extended Block command is used to exit from the Extended Block mode and return the device to Read mode. Four Bus Write operations are required to issue the command.

#### **Block Protect and Chip Unprotect Commands**

Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in APPENDIX A., Tables 23 and 24, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed. Block Protect and Chip Unprotect operations are described in APPENDIX D.

	Length					Bus	Write (	Operati	ons				
Command		1:	1st 2n		2nd 3rd		4th		5th		61	th	
		Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data
Read/Reset	1	Х	F0										
neau/nesei	3	555	AA	2AA	55	Х	F0						
Auto Select	3	555	AA	2AA	55	(BKA) 555	90						
Program	4	555	AA	2AA	55	555	A0	PA	PD				
Double Word Program	3	555	50	PA0	PD0	PA1	PD1						
Unlock Bypass	3	555	AA	2AA	55	555	20						
Unlock Bypass Program	2	х	A0	PA	PD								
Unlock Bypass Reset	2	Х	90	Х	00								
Chip Erase	6	555	AA	2AA	55	555	80	555	AA	2AA	55	555	10
Block Erase	6+	555	AA	2AA	55	555	80	555	AA	2AA	55	BA	30
Erase Suspend	1	BKA	B0										
Erase Resume	1	BKA	30										
Read CFI Query	1	55	98										
Enter Extended Block	3	555	AA	2AA	55	555	88						
Exit Extended Block	4	555	AA	2AA	55	555	90	Х	00				

Table 5. Commands, 16-bit mode,  $\overline{\text{BYTE}} = V_{\text{IH}}$ 

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block, BKA Bank Address. All values in the table are in hexadecimal.

The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when  $\overline{\text{BYTE}}$  is V<sub>IL</sub> or DQ15 when  $\overline{\text{BYTE}}$  is V<sub>IL</sub>.

	ج.					Bus V	Vrite O	peratio	ns				
Command	Length	1:	st	2nd		3rd		4th		5th		6th	
	Ľ	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data
Read/Reset	1	Х	F0										
Reau/Reset	3	AAA	AA	555	55	Х	F0						
Auto Select	3	AAA	AA	555	55	(BKA) AAA	90						
Program	4	AAA	AA	555	55	AAA	A0	PA	PD				
Quadruple Byte Program	5	AAA	55	PA0	PD0	PA1	PD1	PA2	PD2	PA3	PD3		
Unlock Bypass	3	AAA	AA	555	55	AAA	20						
Unlock Bypass Program	2	Х	A0	PA	PD								
Unlock Bypass Reset	2	Х	90	Х	00								
Chip Erase	6	AAA	AA	555	55	AAA	80	AAA	AA	555	55	AAA	10
Block Erase	6+	AAA	AA	555	55	AAA	80	AAA	AA	555	55	BA	30
Erase Suspend	1	BKA	B0										
Erase Resume	1	BKA	30										
Read CFI Query	1	AA	98										
Enter Extended Block	3	AAA	AA	555	55	AAA	88						
Exit Extended Block	4	AAA	AA	555	55	AAA	90	Х	00				

# Table 6. Commands, 8-bit mode, BYTE = VIL

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block. All values in the table are in hexadecimal. The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when BYTE is V<sub>IL</sub> or DQ15 when BYTE is V<sub>IH</sub>.

#### Table 7. Program, Erase Times and Program, Erase Endurance Cycles

Parameter	Min	Typ <sup>(1, 2)</sup>	Max <sup>(2)</sup>	Unit
Chip Erase		40	200 <sup>(3)</sup>	S
Block Erase (64 KBytes)		0.8	6 <sup>(3)</sup>	S
Erase Suspend Latency Time			50 <sup>(4)</sup>	μs
Program (Byte or Word)		10	200 <sup>(4)</sup>	μs
Double Word Program (Byte or Word)		10	200 <sup>(3)</sup>	μs
Chip Program (Byte by Byte)		40	200 <sup>(3)</sup>	S
Chip Program (Word by Word)		20	100 <sup>(3)</sup>	S
Chip Program (Quadruple Byte or Double Word)		10	100 <sup>(3)</sup>	s
Program/Erase Cycles (per Block)	100,000			cycles
Data Retention	20			years

Note: 1. Typical values measured at room temperature and nominal voltages.

2. Sampled, but not 100% tested.

3. Maximum value measured at worst case conditions for both temperature and V<sub>CC</sub> after 100,00 program/erase cycles.

4. Maximum value measured at worst case conditions for both temperature and V<sub>CC</sub>.

# STATUS REGISTER

The M29DW323D has a Status Register that provides information on the current or previous Program or Erase operations executed in each bank. The various bits convey information and errors on the operation. Bus Read operations from any address within the Bank, always read the Status Register during Program and Erase operations. It is also read during Erase Suspend when an address within a block being erased is accessed.

The bits in the Status Register are summarized in Table 8., Status Register Bits.

Data Polling Bit (DQ7). The Data Polling Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Data Polling Bit is output on DQ7 when the Status Register is read.

During Program operations the Data Polling Bit outputs the complement of the bit being programmed to DQ7. After successful completion of the Program operation the memory returns to Read mode and Bus Read operations from the address just programmed output DQ7, not its complement.

During Erase operations the Data Polling Bit outputs '0', the complement of the erased state of DQ7. After successful completion of the Erase operation the memory returns to Read Mode.

In Erase Suspend mode the Data Polling Bit will output a '1' during a Bus Read operation within a block being erased. The Data Polling Bit will change from a '0' to a '1' when the Program/Erase Controller has suspended the Erase operation.

Figure 7., Data Polling Flowchart, gives an example of how to use the Data Polling Bit. A Valid Address is the address being programmed or an address within the block being erased.

**Toggle Bit (DQ6).** The Toggle Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Toggle Bit is output on DQ6 when the Status Register is read.

During Program and Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations at any address. After successful completion of the operation the memory returns to Read mode.

During Erase Suspend mode the Toggle Bit will output when addressing a cell within a block being erased. The Toggle Bit will stop toggling when the Program/Erase Controller has suspended the Erase operation.

Figure 8., Toggle Flowchart, gives an example of how to use the Data Toggle Bit. Figures 14 and 15 describe Toggle Bit timing waveform.

**Error Bit (DQ5).** The Error Bit can be used to identify errors detected by the Program/Erase Controller. The Error Bit is set to '1' when a Program, Block Erase or Chip Erase operation fails to write the correct data to the memory. If the Error Bit is set a Read/Reset command must be issued before other commands are issued. The Error bit is output on DQ5 when the Status Register is read.

Note that the Program command cannot change a bit set to '0' back to '1' and attempting to do so will set DQ5 to '1'. A Bus Read operation to that address will show the bit is still '0'. One of the Erase commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

**Erase Timer Bit (DQ3).** The Erase Timer Bit can be used to identify the start of Program/Erase Controller operation during a Block Erase command. Once the Program/Erase Controller starts erasing the Erase Timer Bit is set to '1'. Before the Program/Erase Controller starts the Erase Timer Bit is set to '0' and additional blocks to be erased may be written to the Command Interface. The Erase Timer Bit is output on DQ3 when the Status Register is read.

Alternative Toggle Bit (DQ2). The Alternative Toggle Bit can be used to monitor the Program/ Erase controller during Erase operations. The Alternative Toggle Bit is output on DQ2 when the Status Register is read.

During Chip Erase and Block Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations from addresses within the blocks being erased. A protected block is treated the same as a block not being erased. Once the operation completes the memory returns to Read mode.

During Erase Suspend the Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read operations from addresses within the blocks being erased. Bus Read operations to addresses within blocks not being erased will output the memory cell data as if in Read mode.

After an Erase operation that causes the Error Bit to be set the Alternative Toggle Bit can be used to identify which block or blocks have caused the error. The Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read Operations from addresses within blocks that have not erased correctly. The Alternative Toggle Bit does not change if the addressed block has erased correctly.

Figures 14 and 15 describe Alternative Toggle Bit timing waveform.

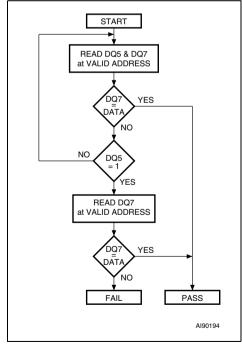


Operation	Address	DQ7	DQ6	DQ5	DQ3	DQ2	RB
Program	Bank Address	DQ7	Toggle	0	-	-	0
Program During Erase Suspend	Bank Address	DQ7	Toggle	0	-	-	0
Program Error	Bank Address	DQ7	Toggle	1	-	-	Hi-Z
Chip Erase	Any Address	0	Toggle	0	1	Toggle	0
Block Erase before	Erasing Block	0	Toggle	0	0	Toggle	0
timeout	Non-Erasing Block	0	Toggle	0	0	Toggle       No Toggle       Toggle	0
Block Erase	Erasing Block	0	Toggle	0	1	Toggle	0
DIOCK ETASE	Non-Erasing Block	0	Toggle	0	1	- - Toggle Toggle No Toggle	0
Erase Suspend	Erasing Block	1	No Toggle	0	-	Toggle	Hi-Z
Elase Suspellu	Non-Erasing Block		Data	read as no	ormal	No Toggle Toggle No Toggle Toggle	Hi-Z
Erase Error	Good Block Address	0	Toggle	1	1	No Toggle	Hi-Z
Erase Error	Faulty Block Address	0	Toggle	1	1	Toggle	Hi-Z

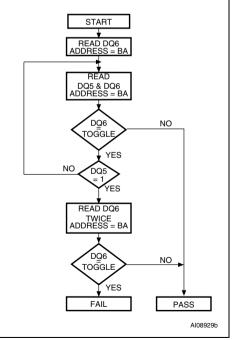
#### Table 8. Status Register Bits

Note: Unspecified data bits should be ignored.

#### Figure 7. Data Polling Flowchart



#### Figure 8. Toggle Flowchart



Note: BA = Address of Bank being Programmed or Erased.

# DUAL OPERATIONS AND MULTIPLE BANK ARCHITECTURE

The Multiple Bank Architecture of the M29DW323DT and M29DW323DB gives greater flexibility for software developers to split the code and data spaces within the memory array. The Dual Operations feature simplifies the software management of the device by allowing code to be executed from one bank while the other bank is being programmed or erased.

The Dual Operations feature means that while programming or erasing in one bank, read operations are possible in the other bank with zero latency.

Only one bank at a time is allowed to be in program or erase mode. If a read operation is required in a bank, which is programming or erasing, the program or erase operation can be suspended.

Also if the suspended operation was erase then a program command can be issued to another block, so the device can have one block in Erase Suspend mode, one programming and other banks in read mode.

By using a combination of these features, read operations are possible at any moment.

Table 9. and Table 10. show the dual operations possible in other banks and in the same bank. Note that only the commonly used commands are represented in these tables.

	Commands allowed in the Other Bank <sup>(1)</sup>									
Status of First Bank <sup>(1)</sup>	Read Array	Read Status Register <sup>(6)</sup>	Read CFI Query	Auto Select	Program	Erase	Erase Suspend	Erase Resume		
Idle	Yes	Yes <sup>(2)</sup>	Yes	Yes	Yes	Yes	Yes <sup>(2)</sup>	Yes <sup>(3)</sup>		
Programming	Yes	No	No	No	-	-	No	No		
Erasing	Yes	No	No	No	-	-	No	No		
Erase Suspended	Yes	Yes	Yes	Yes	Yes	No	-	Yes		

#### Table 9. Dual Operations Allowed In the Other Bank

Note: 1. If one bank is involved in a program or erase operation, then the other bank is available for dual operations.

2. Only after an Erase operation in that bank.

3. Only after an Erase Suspend command in that bank.

#### Table 10. Dual Operations Allowed In Same Bank

Commands allowed in same bank								
Status of bank	Read Array	Read Status Register <sup>(4)</sup>	Read CFI Query	Auto Select	Program	Erase	Erase Suspend	Erase Resume
Idle	Yes	Yes	Yes	Yes	Yes	Yes	Yes <sup>(2)</sup>	Yes <sup>(3)</sup>
Programming	No	Yes	No	No	-	-	No	-
Erasing	No	Yes	No	No	-	No	Yes <sup>(5)</sup>	-
Erase Suspended	Yes <sup>(1)</sup>	Yes <sup>(5)</sup>	Yes	Yes	Yes <sup>(1)</sup>	No	-	Yes <sup>(4)</sup>

Note: 1. Not allowed in the Block or Word that is being erased or programmed.

2. Only after an Erase operation in that bank.

3. Only after an Erase Suspend command in that bank.

4. Read Status Register is not a command. The Status Register can be read during a block program or erase operation.

5. The Status Register can be read by addressing the block being erase suspended.



# MAXIMUM RATING

Stressing the device above the rating listed in the Absolute Maximum Ratings table may cause permanent damage to the device. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Refer also to the Numonyx SURE Program and other relevant quality documents.

Symbol	Parameter	Min	Max	Unit
T <sub>BIAS</sub>	Temperature Under Bias	-50	125	°C
T <sub>STG</sub>	Storage Temperature	-65	150	°C
T <sub>LEAD</sub>	Lead Temperature during Soldering		(1)	°C
V <sub>IO</sub>	Input or Output Voltage <sup>(2,3)</sup>	-0.6	V <sub>CC</sub> +0.6	V
V <sub>CC</sub>	Supply Voltage	-0.6	4	V
V <sub>ID</sub>	Identification Voltage	-0.6	13.5	V
V <sub>PP</sub> <sup>(4)</sup>	Program Voltage	-0.6	13.5	V

#### **Table 11. Absolute Maximum Ratings**

Note: 1. Compliant with the JEDEC Std J-STD-020B (for small body, Sn-Pb or Pb assembly), and the European directive on Restrictions on Hazardous Substances (RoHS) 2002/95/EU.

2. Minimum voltage may undershoot to -2V during transition and for less than 20ns during transitions.

3. Maximum voltage may overshoot to V<sub>CC</sub> +2V during transition and for less than 20ns during transitions.

4. VPP must not remain at 12V for more than a total of 80hrs.



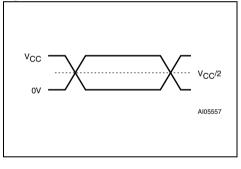
# DC AND AC PARAMETERS

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristics Tables that follow, are derived from tests performed under the Measurement Conditions summarized in Table 12., Operating and AC Measurement Conditions. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

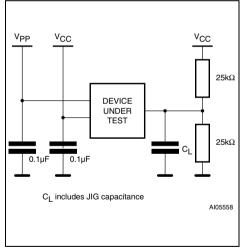
#### Table 12. Operating and AC Measurement Conditions

	M29D	W323D	
Parameter	70	Unit	
	Min	Max	
V <sub>CC</sub> Supply Voltage	C Supply Voltage 2.7 3.6		V
Ambient Operating Temperature	-40	85	°C
Load Capacitance (CL)	3	0	pF
Input Rise and Fall Times		10	ns
Input Pulse Voltages	0 to	0 to V <sub>CC</sub>	
Input and Output Timing Ref. Voltages	Vc	V <sub>CC</sub> /2	

#### Figure 9. AC Measurement I/O Waveform



#### Figure 10. AC Measurement Load Circuit



#### Table 13. Device Capacitance

Symbol	Parameter	Parameter Test Condition		Max	Unit
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0V$		6	pF
C <sub>OUT</sub>	Output Capacitance	$V_{OUT} = 0V$		12	pF

Note: Sampled only, not 100% tested.



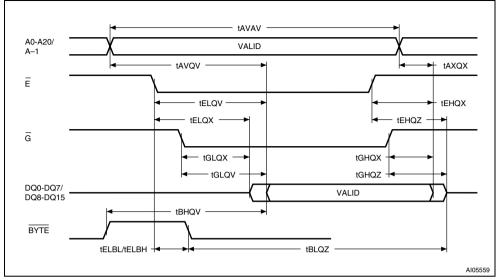
Symbol	Parameter	Test Co	ndition	Min	Max	Unit		
ILI	Input Leakage Current	0V ≤V <sub>IN</sub> ≤V <sub>CC</sub>			±1	μA		
ILO	Output Leakage Current	0V ≤V <sub>OL</sub>	JT ≤V <sub>CC</sub>		±1	μA		
I <sub>CC1</sub> <sup>(2)</sup>	Supply Current (Read)	$\overline{E} = V_{IL}, \overline{0}$ f = 61			10	mA		
I <sub>CC2</sub>	Supply Current (Standby)	Ē = V <sub>CC</sub> RP = V <sub>C</sub>			100	μA		
Icc3 (1,2)			Supply Current (Program/			20	mA	
	Erase)	Controller active $V_{PP}/\overline{WP} = V_{PP}$					20	mA
VIL	Input Low Voltage			-0.5	0.8	V		
VIH	Input High Voltage			0.7V <sub>CC</sub>	V <sub>CC</sub> +0.3	V		
V <sub>PP</sub>	Voltage for V <sub>PP</sub> / <del>WP</del> Program Acceleration	V <sub>CC</sub> = 2.7	7V ±10%	11.5	12.5	v		
IPP	Current for V <sub>PP</sub> /WP Program Acceleration	V <sub>CC</sub> = 2.7	7V ±10%		15	mA		
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 1	.8mA		0.45	V		
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = −100μA		V <sub>CC</sub> -0.4		V		
VID	Identification Voltage			11.5	12.5	V		
V <sub>LKO</sub>	Program/Erase Lockout Supply Voltage			1.8	2.3	v		

#### Table 14. DC Characteristics

Note: 1. Sampled only, not 100% tested.

2. In Dual operations the Supply Current will be the sum of  $I_{CC1}$  (read) and  $I_{CC3}$  (program/erase).

#### Figure 11. Read Mode AC Waveforms

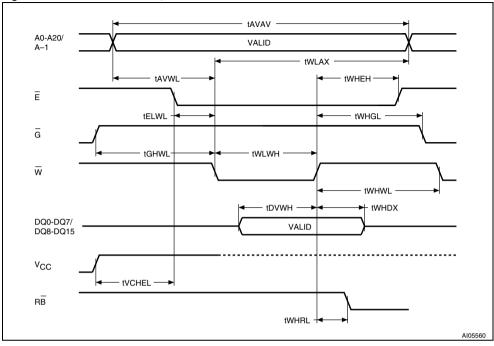


#### Table 15. Read AC Characteristics

Symbol	Alt	Parameter	Test Cond	ition	M29DW323D	Unit
t <sub>AVAV</sub>	t <sub>RC</sub>	Address Valid to Next Address Valid	$\overline{\overline{E}} = V_{IL}, \\ \overline{G} = V_{IL}$	Min	70	ns
tAVQV	tACC	Address Valid to Output Valid	$\overline{\frac{E}{G}} = V_{IL},$ $\overline{G} = V_{IL}$	Max	70	ns
t <sub>ELQX</sub> <sup>(1)</sup>	t <sub>LZ</sub>	Chip Enable Low to Output Transition	$\overline{G} = V_{IL}$	Min	0	ns
t <sub>ELQV</sub>	t <sub>CE</sub>	Chip Enable Low to Output Valid	$\overline{G} = V_{IL}$	Мах	70	ns
t <sub>GLQX</sub> <sup>(1)</sup>	t <sub>OLZ</sub>	Output Enable Low to Output Transition	$\overline{E} = V_{IL}$	Min	0	ns
t <sub>GLQV</sub>	tOE	Output Enable Low to Output Valid	$\overline{E} = V_{IL}$	Мах	30	ns
t <sub>EHQZ</sub> <sup>(1)</sup>	t <sub>HZ</sub>	Chip Enable High to Output Hi-Z	$\overline{G} = V_{IL}$	Мах	25	ns
t <sub>GHQZ</sub> <sup>(1)</sup>	tDF	Output Enable High to Output Hi-Z	$\overline{E} = V_{IL}$	Мах	25	ns
tehax tghax t <sub>AXQX</sub>	t <sub>OH</sub>	Chip Enable, Output Enable or Address Transition to Output Transition		Min	0	ns
t <sub>ELBL</sub> t <sub>ELBH</sub>	t <sub>ELFL</sub> t <sub>ELFH</sub>	Chip Enable to BYTE Low or High		Max	5	ns
t <sub>BLQZ</sub>	t <sub>FLQZ</sub>	BYTE Low to Output Hi-Z		Мах	25	ns
t <sub>BHQV</sub>	t <sub>FHQV</sub>	BYTE High to Output Valid		Мах	30	ns

Note: 1. Sampled only, not 100% tested.



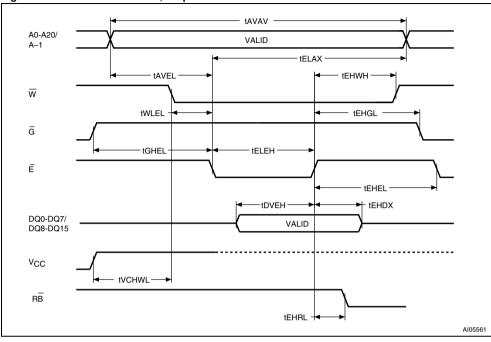


#### Figure 12. Write AC Waveforms, Write Enable Controlled

#### Table 16. Write AC Characteristics, Write Enable Controlled

Symbol	Alt	Parameter		M29DW323D	Unit
tavav	twc	Address Valid to Next Address Valid	Min	70	ns
t <sub>ELWL</sub>	t <sub>CS</sub>	Chip Enable Low to Write Enable Low	Min	0	ns
twlwh	t <sub>WP</sub>	Write Enable Low to Write Enable High	Min	45	ns
t <sub>DVWH</sub>	t <sub>DS</sub>	Input Valid to Write Enable High	Min	45	ns
tWHDX	t <sub>DH</sub>	Write Enable High to Input Transition	Min	0	ns
t <sub>WHEH</sub>	t <sub>CH</sub>	Write Enable High to Chip Enable High	Min	0	ns
twhwL	t <sub>WPH</sub>	Write Enable High to Write Enable Low	Min	30	ns
tavwl	tas	Address Valid to Write Enable Low	Min	0	ns
t <sub>WLAX</sub>	t <sub>AH</sub>	Write Enable Low to Address Transition	Min	45	ns
tGHWL		Output Enable High to Write Enable Low	Min	0	ns
twhgL	tOEH	Write Enable High to Output Enable Low	Min	0	ns
t <sub>WHRL</sub> <sup>(1)</sup>	tBUSY	Program/Erase Valid to RB Low	Max	30	ns
<b>t</b> VCHEL	t <sub>VCS</sub>	V <sub>CC</sub> High to Chip Enable Low	Min	50	μs

Note: 1. Sampled only, not 100% tested.



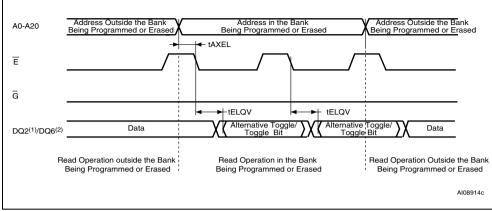
#### Figure 13. Write AC Waveforms, Chip Enable Controlled

Table 17, Write	AC Characteristics,	Chip Enab	le Controlled
	Ao onuluotonotioo,		

Symbol	Alt	Parameter		M29DW323D	Unit
tavav	twc	Address Valid to Next Address Valid	Min	70	ns
tWLEL	tws	Write Enable Low to Chip Enable Low	Min	0	ns
tELEH	tCP	Chip Enable Low to Chip Enable High	Min	45	ns
t <sub>DVEH</sub>	t <sub>DS</sub>	Input Valid to Chip Enable High	Min	45	ns
t <sub>EHDX</sub>	t <sub>DH</sub>	Chip Enable High to Input Transition	Min	0	ns
t <sub>EHWH</sub>	t <sub>WH</sub>	Chip Enable High to Write Enable High	Min	0	ns
t <sub>EHEL</sub>	t <sub>CPH</sub>	Chip Enable High to Chip Enable Low	Min	30	ns
t <sub>AVEL</sub>	t <sub>AS</sub>	Address Valid to Chip Enable Low	Min	0	ns
t <sub>ELAX</sub>	t <sub>AH</sub>	Chip Enable Low to Address Transition	Min	45	ns
<b>t</b> GHEL		Output Enable High Chip Enable Low	Min	0	ns
t <sub>EHGL</sub>	tOEH	Chip Enable High to Output Enable Low	Min	0	ns
t <sub>EHRL</sub> <sup>(1)</sup>	t <sub>BUSY</sub>	Program/Erase Valid to RB Low	Max	30	ns
t <sub>VCHWL</sub>	t <sub>VCS</sub>	V <sub>CC</sub> High to Write Enable Low	Min	50	μs

Note: 1. Sampled only, not 100% tested.



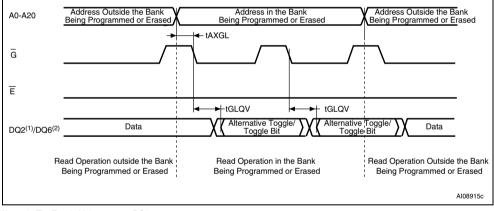


# Figure 14. Toggle and Alternative Toggle Bits Mechanism, Chip Enable Controlled

Note: 1. The Toggle bit is output on DQ6.

2. The Alternative Toggle bit is output on DQ2.

# Figure 15. Toggle and Alternative Toggle Bits Mechanism, Output Enable Controlled



Note: 1. The Toggle bit is output on DQ6.

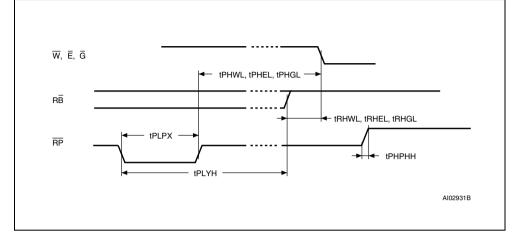
2. The Alternative Toggle bit is output on DQ2.

# Table 18. Toggle and Alternative Toggle Bits AC Characteristics

Symbol	Alt	Parameter		M29DW323D	Unit
t <sub>AXEL</sub>		Address Transition to Chip Enable Low	Min	10	ns
taxgl		Address Transition to Output Enable Low	Min	10	ns

Note: t<sub>ELQV</sub> and t<sub>GLQV</sub> values are presented in Table 15., Read AC Characteristics.

#### Figure 16. Reset/Block Temporary Unprotect AC Waveforms

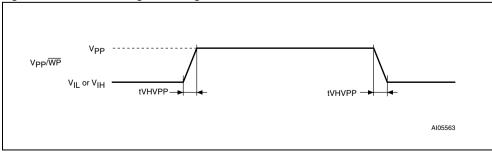


# Table 19. Reset/Block Temporary Unprotect AC Characteristics

Symbol	Alt	Parameter		M29DW323D	Unit
t <sub>PHWL</sub> <sup>(1)</sup> t <sub>PHEL</sub> t <sub>PHGL</sub> <sup>(1)</sup>	t <sub>RH</sub>	RP High to Write Enable Low, Chip Enable Low, Output Enable Low	Min	50	ns
t <sub>RHWL</sub> <sup>(1)</sup> t <sub>RHEL</sub> <sup>(1)</sup> t <sub>RHGL</sub> <sup>(1)</sup>	t <sub>RB</sub>	RB High to Write Enable Low, Chip Enable Low, Output Enable Low	Min	0	ns
t <sub>PLPX</sub>	t <sub>RP</sub>	RP Pulse Width	Min	500	ns
<b>t</b> PLYH	tREADY	RP Low to Read Mode	Max	50	μs
t <sub>PHPHH</sub> <sup>(1)</sup>	tvidr	RP Rise Time to VID	Min	500	ns
t <sub>VHVPP</sub> <sup>(1)</sup>		V <sub>PP</sub> Rise and Fall Time	Min	250	ns

Note: 1. Sampled only, not 100% tested.

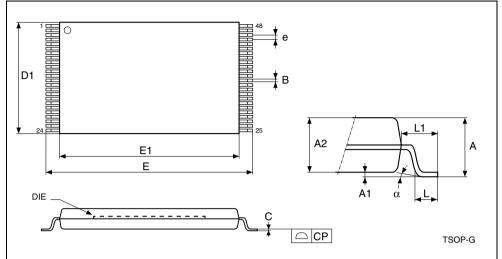
#### Figure 17. Accelerated Program Timing Waveforms





# PACKAGE MECHANICAL



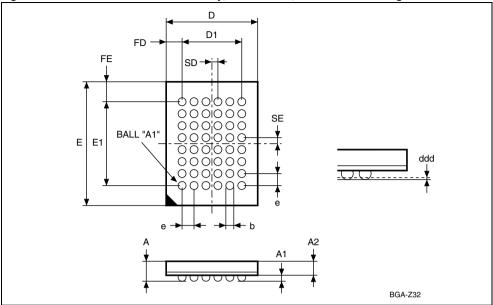


Note: Drawing not to scale.

#### Table 20. TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Package Mechanical Data

0hal	millimeters			inches		
Symbol	Тур	Min	Max	Тур	Min	Max
А			1.200			0.0472
A1	0.100	0.050	0.150	0.0039	0.0020	0.0059
A2	1.000	0.950	1.050	0.0394	0.0374	0.0413
В	0.220	0.170	0.270	0.0087	0.0067	0.0106
С		0.100	0.210		0.0039	0.0083
СР			0.080			0.0031
D1	12.000	11.900	12.100	0.4724	0.4685	0.4764
E	20.000	19.800	20.200	0.7874	0.7795	0.7953
E1	18.400	18.300	18.500	0.7244	0.7205	0.7283
е	0.500	-	-	0.0197	-	-
L	0.600	0.500	0.700	0.0236	0.0197	0.0276
L1	0.800			0.0315		
α	3	0	5	3	0	5

#### Figure 19. TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Bottom View Package Outline



Note: Drawing not to scale.

#### Table 21. TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Package Mechanical Data

Symbol	millimeters			inches		
	Тур	Min	Max	Тур	Min	Max
А			1.200			0.0472
A1		0.260			0.0102	
A2			0.900			0.0354
b		0.350	0.450		0.0138	0.0177
D	6.000	5.900	6.100	0.2362	0.2323	0.2402
D1	4.000	-	-	0.1575	-	-
ddd			0.100			0.0039
Е	8.000	7.900	8.100	0.3150	0.3110	0.3189
E1	5.600	-	-	0.2205	-	-
е	0.800	-	-	0.0315	-	-
FD	1.000	-	-	0.0394	-	-
FE	1.200	-	-	0.0472	-	-
SD	0.400	-	-	0.0157	-	-
SE	0.400	-	-	0.0157	-	-



# PART NUMBERING

#### Table 22. Ordering Information Scheme

Example:	M29DW323DB	70 N 1 T
Device Type		
M29		
Architecture		
D = Dual Operation		
Operating Voltage		
$W = V_{CC} = 2.7 \text{ to } 3.6 \text{V}$		
Device Function		
323D = 32 Mbit (x8/x16), Boot Block, 1/4-3/4 partition	ing	
Array Matrix		
T = Top Boot		
B = Bottom Boot		
Speed		
70 = 70 ns		
70 = 70 113		
Deskawa		
Package		
N = TSOP48: 12 x 20 mm		
ZE = TFBGA48: 6 x 8mm, 0.8mm pitch		
Temperature Range		
1 = 0 to 70 °C		
6 = -40 to 85 °C		
Option		

Blank = Standard Packing T = Tape & Reel Packing E = Lead-free Package, Standard Packing F = Lead-free Package, Tape & Reel Packing

Note: This product is also available with the Extended Block factory locked. For further details and ordering information contact your nearest Numonyx sales office.

Devices are shipped from the factory with the memory content bits erased to '1'.

For a list of available options (Speed, Package, etc.) or for further information on any aspect of this device, please contact the Numonyx Sales Office nearest to you.

# **APPENDIX A. BLOCK ADDRESSES**

# Table 23. Top Boot Block Addresses, M29DW323DT

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	0	64/32	Protection Group	000000h-00FFFFh	000000h-07FFFh
	1	64/32		010000h-01FFFFh	008000h-0FFFFh
	2	64/32	Protection Group	020000h-02FFFFh	010000h-17FFFh
	3	64/32	1 [	030000h-03FFFFh	018000h-01FFFFh
	4	64/32		040000h-04FFFFh	020000h-027FFFh
	5	64/32	Protection Group	050000h-05FFFFh	028000h-02FFFFh
	6	64/32	Fiolection Group	060000h-06FFFFh	030000h-037FFFh
	7	64/32	1 [	070000h-07FFFFh	038000h-03FFFFh
	8	64/32		080000h-08FFFFh	040000h-047FFFh
	9	64/32	Drotaction Crown	090000h-09FFFFh	048000h-04FFFFh
	10	64/32	<ul> <li>Protection Group</li> </ul>	0A0000h-0AFFFFh	050000h-057FFFh
	11	64/32	1 1	0B0000h-0BFFFFh	058000h-05FFFFh
	12	64/32		0C0000h-0CFFFFh	060000h-067FFFh
	13	64/32	Protection Group	0D0000h-0DFFFFh	068000h-06FFFFh
	14	64/32		0E0000h-0EFFFFh	070000h-077FFFh
к В	15	64/32	1 1	0F0000h-0FFFFFh	078000h-07FFFFh
Bank I	16	64/32		100000h-10FFFFh	080000h-087FFFh
	17	64/32	Protection Group	110000h-11FFFFh	088000h-08FFFFh
	18	64/32	- Protection Group	120000h-12FFFFh	090000h-097FFFh
	19	64/32	1 [	130000h-13FFFFh	098000h-09FFFFh
	20	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
	21	64/32	Drotaction Crown	150000h-15FFFFh	0A8000h-0AFFFFh
	22	64/32	Protection Group	160000h-16FFFFh	0B0000h-0B7FFFh
	23	64/32	1 [	170000h-17FFFFh	0B8000h-0BFFFFh
	24	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
	25	64/32		190000h-19FFFFh	0C8000h-0CFFFFh
	26	64/32	<ul> <li>Protection Group</li> </ul>	1A0000h-1AFFFFh	0D0000h-0D7FFFh
	27	64/32	] [	1B0000h-1BFFFFh	0D8000h-0DFFFFh
	28	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFFh
	29	64/32	Protection Group	1D0000h-1DFFFFh	0E8000h-0EFFFFh
	30	64/32		1E0000h-1EFFFFh	0F0000h-0F7FFFh
	31	64/32	]	1F0000h-1FFFFFh	0F8000h-0FFFFFh



Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	32	64/32	Brotaction Crown	200000h-20FFFFh	100000h-107FFFh
	33	64/32		210000h-21FFFFh	108000h-10FFFFh
	34	64/32	Protection Group	220000h-22FFFFh	110000h-117FFFh
	35	64/32		230000h-23FFFFh	118000h-11FFFFh
	36	64/32		240000h-24FFFFh	120000h-127FFFh
	37	64/32	Drotaction Crown	250000h-25FFFFh	128000h-12FFFFh
	38	64/32	Protection Group	260000h-26FFFFh	130000h-137FFFh
к В	39	64/32	1	270000h-27FFFFh	138000h-13FFFFh
Bank I	40	64/32		280000h-28FFFFh	140000h-147FFFh
	41	64/32	Durata ati an Orang	290000h-29FFFFh	148000h-14FFFFh
	42	64/32	Protection Group	2A0000h-2AFFFFh	150000h-157FFFh
	43	64/32		2B0000h-2BFFFFh	158000h-15FFFFh
	44	64/32	Protection Group	2C0000h-2CFFFFh	160000h-167FFFh
	45	64/32		2D0000h-2DFFFFh	168000h-16FFFFh
	46	64/32		2E0000h-2EFFFFh	170000h-177FFFh
	47	64/32		2F0000h-2FFFFFh	178000h-17FFFFh
	48	64/32	Protection Group	300000h-30FFFFh	180000h-187FFFh
	49	64/32		310000h-31FFFFh	188000h-18FFFFh
	50	64/32		320000h-32FFFFh	190000h-197FFFh
	51	64/32		330000h-33FFFFh	198000h-19FFFFh
	52	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
	53	64/32	Protection Group	350000h-35FFFFh	1A8000h-1AFFFFh
4	54	64/32		360000h-36FFFFh	1B0000h-1B7FFFh
Bank A	55	64/32		370000h-37FFFFh	1B8000h-1BFFFFh
ä	56	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
	57	64/32	Protection Group	390000h-39FFFFh	1C8000h-1CFFFFh
	58	64/32		3A0000h-3AFFFFh	1D0000h-1D7FFFh
	59	64/32	]	3B0000h-3BFFFFh	1D8000h-1DFFFFh
	60	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
	61	64/32	Protection Group	3D0000h-3DFFFFh	1E8000h-1EFFFFh
	62	64/32		3E0000h-3EFFFFh	1F0000h-1F7FFFh

# M29DW323DT, M29DW323DB

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	63	8/4	Protection Group	3F0000h-3F1FFFh <sup>(1)</sup>	1F8000h-1F8FFFh <sup>(1)</sup>
	64	8/4	Protection Group	3F2000h-3F3FFFh <sup>(1)</sup>	1F9000h-1F9FFFh <sup>(1)</sup>
	65	8/4	Protection Group	3F4000h-3F5FFFh <sup>(1)</sup>	1FA000h-1FAFFFh <sup>(1)</sup>
kА	66	8/4	Protection Group	3F6000h-3F7FFFh <sup>(1)</sup>	1FB000h-1FBFFFh <sup>(1)</sup>
Bank	67	8/4	Protection Group	3F8000h-3F9FFFh <sup>(1)</sup>	1FC000h-1FCFFFh <sup>(1)</sup>
	68	8/4	Protection Group	3FA000h-3FBFFFh <sup>(1)</sup>	1FD000h-1FDFFFh <sup>(1)</sup>
	69	8/4	Protection Group	3FC000h-3FDFFFh <sup>(1)</sup>	1FE000h-1FEFFFh <sup>(1)</sup>
	70	8/4	Protection Group	3FE000h-3FFFFFh <sup>(1)</sup>	1FF000h-1FFFFFh <sup>(1)</sup>

Note: 1. Used as the Extended Block Addresses in Extended Block mode.



Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(×8)	(x16)
-	0	8/4	Protection Group	000000h-001FFFh <sup>(1)</sup>	000000h-000FFFh <sup>(1)</sup>
	1	8/4	Protection Group	002000h-003FFFh <sup>(1)</sup>	001000h-001FFFh <sup>(1)</sup>
	2	8/4	Protection Group	004000h-005FFFh <sup>(1)</sup>	002000h-002FFFh <sup>(1)</sup>
	3	8/4	Protection Group	006000h-007FFFh <sup>(1)</sup>	003000h-003FFFh <sup>(1)</sup>
	4	8/4	Protection Group	008000h-009FFFh <sup>(1)</sup>	004000h-004FFFh <sup>(1)</sup>
	5	8/4	Protection Group	00A000h-00BFFFh <sup>(1)</sup>	005000h-005FFFh <sup>(1)</sup>
	6	8/4	Protection Group	00C000h-00DFFFh <sup>(1)</sup>	006000h-006FFFh <sup>(1)</sup>
	7	8/4	Protection Group	00E000h-00FFFFh <sup>(1)</sup>	007000h-007FFFh <sup>(1)</sup>
	8	64/32		010000h-01FFFFh	008000h-00FFFFh
	9	64/32	Protection Group	020000h-02FFFFh	010000h-017FFFh
k A	10	64/32		030000h-03FFFFh	018000h-01FFFFh
Bank A	11	64/32		040000h-04FFFFh	020000h-027FFFh
	12	64/32	Drotaction Crown	050000h-05FFFFh	028000h-02FFFFh
	13	64/32	Protection Group	060000h-06FFFFh	030000h-037FFFh
	14	64/32		070000h-07FFFFh	038000h-03FFFFh
	15	64/32		080000h-08FFFFh	040000h-047FFFh
	16	64/32		090000h-09FFFFh	048000h-04FFFFh
	17	64/32	Protection Group	0A0000h-0AFFFFh	050000h-057FFFh
	18	64/32		0B0000h-0BFFFFh	058000h-05FFFFh
	19	64/32		0C0000h-0CFFFFh	060000h-067FFFh
	20	64/32		0D0000h-0DFFFFh	068000h-06FFFFh
	21	64/32	Protection Group	0E0000h-0EFFFFh	070000h-077FFFh
	22	64/32		0F0000h-0FFFFFh	078000h-07FFFFh
	23	64/32		100000h-10FFFFh	080000h-087FFFh
	24	64/32		110000h-11FFFFh	088000h-08FFFFh
	25	64/32	Protection Group	120000h-12FFFFh	090000h-097FFFh
kВ	26	64/32	1	130000h-13FFFFh	098000h-09FFFFh
Bank I	27	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
	28	64/32	Dratastic - Ora-	150000h-15FFFFh	0A8000h-0AFFFFh
	29	64/32	Protection Group	160000h-16FFFFh	0B0000h-0B7FFFh
	30	64/32	1	170000h-17FFFFh	0B8000h-0BFFFFh

### Table 24. Bottom Boot Block Addresses, M29DW323DB

## M29DW323DT, M29DW323DB

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	31	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
	32	64/32	Ducto etica Orean	190000h-19FFFFh	0C8000h-0CFFFFh
-	33	64/32	Protection Group	1A0000h-1AFFFFh	0D0000h-0D7FFFh
	34	64/32		1B0000h-1BFFFFh	0D8000h-0DFFFFh
	35	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFFh
	36	64/32	Protection Group	1D0000h-1DFFFFh	0E8000h-0EFFFFh
	37	64/32	- Protection Group	1E0000h-1EFFFFh	0F0000h-0F7FFFh
	38	64/32		1F0000h-1FFFFFh	0F8000h-0FFFFFh
	39	64/32		200000h-20FFFFh	100000h-107FFFh
	40	64/32	Ducto ation One or	210000h-21FFFFh	108000h-10FFFFh
	41	64/32	Protection Group	220000h-22FFFFh	110000h-117FFFh
	42	64/32		230000h-23FFFFh	118000h-11FFFFh
	43	64/32	Protection Group	240000h-24FFFFh	120000h-127FFFh
	44	64/32		250000h-25FFFFh	128000h-12FFFFh
	45	64/32		260000h-26FFFFh	130000h-137FFFh
k B	46	64/32	]	270000h-27FFFFh	138000h-13FFFFh
Bank	47	64/32	Protection Group	280000h-28FFFFh	140000h-147FFFh
	48	64/32		290000h-29FFFFh	148000h-14FFFFh
	49	64/32		2A0000h-2AFFFFh	150000h-157FFFh
	50	64/32	]	2B0000h-2BFFFFh	158000h-15FFFFh
	51	64/32		2C0000h-2CFFFFh	160000h-167FFFh
	52	64/32	Protection Group	2D0000h-2DFFFFh	168000h-16FFFFh
	53	64/32	- Protection Group	2E0000h-2EFFFFh	170000h-177FFFh
	54	64/32	]	2F0000h-2FFFFFh	178000h-17FFFFh
	55	64/32		300000h-30FFFFh	180000h-187FFFh
	56	64/32	Protection Group	310000h-31FFFFh	188000h-18FFFFh
	57	64/32	<ul> <li>Protection Group</li> </ul>	320000h-32FFFFh	190000h-197FFFh
	58	64/32	] [	330000h-33FFFFh	198000h-19FFFFh
	59	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
	60	64/32	Protection Group	350000h-35FFFFh	1A8000h-1AFFFFh
	61	64/32	Frotection Group	360000h-36FFFFh	1B0000h-1B7FFFh
	62	64/32	] [	370000h-37FFFFh	1B8000h-1BFFFFh

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	63	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
	64	64/32	Protection Group	390000h-39FFFFh	1C8000h-1CFFFFh
	65	64/32	Frotection Group	3A0000h-3AFFFFh	1D0000h-1D7FFFh
ы Ш	66	64/32		3B0000h-3BFFFFh	1D8000h-1DFFFFh
Bank	67	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
	68	64/32	Protection Group	3D0000h-3DFFFFh	1E8000h-1EFFFFh
	69	64/32		3E0000h-3EFFFFh	1F0000h-1F7FFFh
	70	64/32	Protection Group	3F0000h-3FFFFFh	1F8000h-1FFFFFh

Note: 1. Used as the Extended Block Addresses in Extended Block mode.



# APPENDIX B. COMMON FLASH INTERFACE (CFI)

The Common Flash Interface is a JEDEC approved, standardized data structure that can be read from the Flash memory device. It allows a system software to query the device to determine various electrical and timing parameters, density information and functions supported by the memory. The system can interface easily with the device, enabling the software to upgrade itself when necessary.

When the CFI Query Command is issued the device enters CFI Query mode and the data structure is read from the memory. Tables 25, 26, 27, 28, 29 and 30 show the addresses used to retrieve the data.

The CFI data structure also contains a security area where a 64 bit unique security number is written (see Table 30., Security Code Area). This area can be accessed only in Read mode by the final user. It is impossible to change the security number after it has been written by Numonyx.

Add	ress	Sub-section Name	Description	
x16	x8		Description	
10h	20h	CFI Query Identification String	Command set ID and algorithm data offset	
1Bh	36h	System Interface Information	Device timing & voltage information	
27h	4Eh	Device Geometry Definition	Flash device layout	
40h	80h	Primary Algorithm-specific Extended Query table	Additional information specific to the Primary Algorithm (optional)	
61h	C2h	Security Code Area	64 bit unique device number	

#### Table 25. Query Structure Overview

Note: Query data are always presented on the lowest order data outputs.

#### Table 26. CFI Query Identification String

Add	Address		Description	Value
x16	x8	Data	Description	value
10h	20h	0051h		"Q"
11h	22h	0052h	Query Unique ASCII String "QRY"	"R"
12h	24h	0059h		
13h	26h	0002h	Primary Algorithm Command Set and Control Interface ID code 16 bit	
14h	28h	0000h	ID code defining a specific algorithm	Compatible
15h	2Ah	0040h		
16h	2Ch	0000h	Address for Primary Algorithm extended Query table (see Table 29.)	P = 40h
17h	2Eh	0000h	Alternate Vendor Command Set and Control Interface ID Code second	NA
18h	30h	0000h	vendor - specified algorithm supported	
19h	32h	0000h	Address for Alternate Algorithm extended Query table	NA
1Ah	34h	0000h		INA

Note: Query data are always presented on the lowest order data outputs (DQ7-DQ0) only. DQ8-DQ15 are '0'.



#### Table 27. CFI Query System Interface Information

Add	Address		Description	Value
x16	x8	Data	Description	value
1Bh	36h	0027h	V <sub>CC</sub> Logic Supply Minimum Program/Erase voltage bit 7 to 4BCD value in volts bit 3 to 0BCD value in 100 mV	2.7V
1Ch	38h	0036h	V <sub>CC</sub> Logic Supply Maximum Program/Erase voltage bit 7 to 4BCD value in volts bit 3 to 0BCD value in 100 mV	3.6V
1Dh	3Ah	00B5h	V <sub>PP</sub> [Programming] Supply Minimum Program/Erase voltage bit 7 to 4HEX value in volts bit 3 to 0BCD value in 100 mV	11.5V
1Eh	3Ch	00C5h	V <sub>PP</sub> [Programming] Supply Maximum Program/Erase voltage bit 7 to 4HEX value in volts bit 3 to 0BCD value in 100 mV	12.5V
1Fh	3Eh	0004h	Typical timeout per single byte/word program = $2^n \mu s$	16µs
20h	40h	0000h	Typical timeout for minimum size write buffer program = $2^{n} \mu s$	NA
21h	42h	000Ah	Typical timeout per individual block erase = 2 <sup>n</sup> ms	1s
22h	44h	0000h	Typical timeout for full Chip Erase = 2 <sup>n</sup> ms	NA
23h	46h	0004h	Maximum timeout for byte/word program = 2 <sup>n</sup> times typical	256 µs
24h	48h	0000h	Maximum timeout for write buffer program = 2 <sup>n</sup> times typical	NA
25h	4Ah	0003h	Maximum timeout per individual block erase = 2 <sup>n</sup> times typical	8 s
26h	4Ch	0000h	Maximum timeout for Chip Erase = 2 <sup>n</sup> times typical	NA

#### Table 28. Device Geometry Definition

Address		Data	Description	Malua	
x16	x8	Data	Description	Value	
27h	4Eh	0016h	Device Size = 2 <sup>n</sup> in number of bytes	4 MByte	
28h	50h	0002h	Flash Device Interface Code description	x8, x16	
29h	52h	0000h		Async.	
2Ah 2Bh	54h 56h	0000h 0000h	Maximum number of bytes in multi-byte program or page = 2 <sup>n</sup>	NA	
2Ch	58h	0002h	Number of Erase Block Regions. It specifies the number of regions containing contiguous Erase Blocks of the same size.	2	
2Dh	5Ah	0007h	Region 1 Information	8	
2Eh	5Ch	0000h	Number of Erase Blocks of identical size = 0007h+1		
2Fh	5Eh	0020h	Region 1 Information	8Kbyte	
30h	60h	0000h	Block size in Region 1 = 0020h * 256 byte		
31h	62h	003Eh	Region 2 Information	63	
32h	64h	0000h	Number of Erase Blocks of identical size = 003Eh+1		
33h	66h	0000h	Region 2 Information	64Kbyte	
34h	68h	0001h	Block size in Region 2 = 0100h * 256 byte		

Note: For the M29DW323DB, Region 1 corresponds to addresses 000000h to 007FFFh and Region 2 to addresses 008000h to 1FFFFh. For the M29DW323DT, Region 1 corresponds to addresses 1F8000h to 1FFFFFh and Region 2 to addresses 000000h to 1F7FFFh.

## Table 29. Primary Algorithm-Specific Extended Query Table

Ade	Address				
x16	x8	Data	Description	Value	
40h	80h	0050h		"P"	
41h	82h	0052h	Primary Algorithm extended Query table unique ASCII string "PRI"	"R"	
42h	84h	0049h		"I"	
43h	86h	0031h	Major version number, ASCII	"1"	
44h	88h	0030h	Minor version number, ASCII	"0"	
45h	8Ah	0000h	Address Sensitive Unlock (bits 1 to 0) 20 = required, 01= not required Silicon Revision Number (bits 7 to 2)		
46h	8Ch	0002h	Erase Suspend 00 = not supported, 01 = Read only, 02 = Read and Write		
47h	8Eh	0001h	Block Protection 00 = not supported, x = number of blocks in per group		
48h	90h	0001h	Temporary Block Unprotect 00 = not supported, 01 = supported		
49h	92h	0004h	Block Protect /Unprotect 04 = M29DW323D	04	
4Ah	94h	0030h	Simultaneous Operations, x = number of blocks in Bank B	48	
4Bh	96h	0000h	Burst Mode, 00 = not supported, 01 = supported	No	
4Ch	98h	0000h	Page Mode, 00 = not supported, 01 = 4 page word, 02 = 8 page word	No	
4Dh	9Ah	00B5h	V <sub>PP</sub> Supply Minimum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV		
4Eh	9Ch	00C5h	V <sub>PP</sub> Supply Maximum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV		
4Fh	9Eh	000xh	Top/Bottom Boot Block Flag 02h = Bottom Boot device, 03h = Top Boot device	-	

## Table 30. Security Code Area

Add	Address		Description		
x16	x8	Data	Description		
61h	C3h, C2h	XXXX			
62h	C5h, C4h	XXXX	C4 hituniaus davies number		
63h	C7h, C6h	XXXX	64 bit: unique device number		
64h	C9h, C8h	XXXX			



## APPENDIX C. EXTENDED MEMORY BLOCK

The M29DW323D has an extra block, the Extended Block, that can be accessed using a dedicated command.

This Extended Block is 32 KWords in x16 mode and 64 KBytes in x8 mode. It is used as a security block (to provide a permanent security identification number) or to store additional information.

The Extended Block is either Factory Locked or Customer Lockable, its status is indicated by bit DQ7. This bit is permanently set to either '1' or '0' at the factory and cannot be changed. When set to '1', it indicates that the device is factory locked and the Extended Block is protected. When set to '0', it indicates that the device is customer lockable and the Extended Block is unprotected. Bit DQ7 being permanently locked to either '1' or '0' is another security feature which ensures that a customer lockable device cannot be used instead of a factory locked one.

Bit DQ7 is the most significant bit in the Extended Block Verify Code and a specific procedure must be followed to read it. See "Extended Memory Block Verify Code" in Tables 3 and 4, Bus Operations, BYTE =  $V_{IL}$  and Bus Operations, BYTE =  $V_{IH}$ , respectively, for details of how to read bit DQ7.

The Extended Block can only be accessed when the device is in Extended Block mode. For details of how the Extended Block mode is entered and exited, refer to the Enter Extended Block Command and Exit Extended Block Command paragraphs, and to Tables 5 and 6, "Commands, 16-bit mode, BYTE =  $V_{IH}$ " and "Commands, 8-bit mode, BYTE =  $V_{IL}$ ", respectively.

### Factory Locked Extended Block

In devices where the Extended Block is factory locked, the Security Identification Number is written to the Extended Block address space (see Table 31., Extended Block Address and Data) in the factory. The DQ7 bit is set to '1' and the Extended Block cannot be unprotected.

#### Customer Lockable Extended Block

A device where the Extended Block is customer lockable is delivered with the DQ7 bit set to '0' and the Extended Block unprotected. It is up to the customer to program and protect the Extended Block but care must be taken because the protection of the Extended Block is not reversible.

There are two ways of protecting the Extended Block:

- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the In-System Technique with RP either at V<sub>IH</sub> or at V<sub>ID</sub> (refer to APPENDIX D., In-System Technique and to the corresponding flowcharts, Figures 22 and 23, for a detailed explanation of the technique).
- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the Programmer Technique (refer to APPENDIX D., Programmer Technique and to the corresponding flowcharts, Figures 20 and 21, for a detailed explanation of the technique).

Once the Extended Block is programmed and protected, the Exit Extended Block command must be issued to exit the Extended Block mode and return the device to Read mode.

Device	Addr	Address <sup>(1)</sup>		Data		
Device	x8	x16	Factory Locked	Customer Lockable		
M29DW323DT	3F0000h-3F000Fh	1F8000h-1F8007h	Security Identification Number	Determined by Customer		
	3F0010h-3FFFFFh	1F8008h-1FFFFFh	Unavailable	Customer		
M29DW323DB	000000h-00000Fh	000000h-000007h	Security Identification Number	Determined by Customer		
	000010h-00FFFFh	000008h-007FFFh	Unavailable	Customer		

#### Table 31. Extended Block Address and Data

Note: 1. See Tables 23 and 24, Top and Bottom Boot Block Addresses.

# APPENDIX D. BLOCK PROTECTION

Block protection can be used to prevent any operation from modifying the data stored in the memory. The blocks are protected in groups, refer to APPENDIX A., Tables 23 and 24 for details of the Protection Groups. Once protected, Program and Erase operations within the protected group fail to change the data.

There are three techniques that can be used to control Block Protection, these are the Programmer technique, the In-System technique and Temporary Unprotection. Temporary Unprotection is controlled by the Reset/Block Temporary Unprotection pin, RP; this is described in the Signal Descriptions section.

#### **Programmer Technique**

The Programmer technique uses high ( $V_{ID}$ ) voltage levels on some of the bus pins. These cannot be achieved using a standard microprocessor bus, therefore the technique is recommended only for use in Programming Equipment.

To protect a group of blocks follow the flowchart in Figure 20., Programmer Equipment Group Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all groups can be unprotected at the same time. To unprotect the chip follow Figure 21., Programmer Equipment Chip Unprotect Flowchart. Table 32., Programmer Technique Bus Operations, BYTE = V<sub>IH</sub> or V<sub>IL</sub>, gives a summary of each operation.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is

specified, it is followed as closely as possible. Do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

### In-System Technique

The In-System technique requires a high voltage level on the Reset/Blocks Temporary Unprotect pin,  $\overline{RP}^{(1)}$ . This can be achieved without violating the maximum ratings of the components on the microprocessor bus, therefore this technique is suitable for use after the memory has been fitted to the system.

To protect a group of blocks follow the flowchart in Figure 22., In-System Equipment Group Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all the groups can be unprotected at the same time. To unprotect the chip follow Figure 23., In-System Equipment Chip Unprotect Flowchart.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not allow the microprocessor to service interrupts that will upset the timing and do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

Note: 1.  $\overline{\text{RP}}$  can be either at V<sub>IH</sub> or at V<sub>ID</sub> when using the In-System Technique to protect the Extended Block.

Operation	Ē	G	W	Address Inputs A0-A20	Data Inputs/Outputs DQ15A-1, DQ14-DQ0
Block (Group) Protect <sup>(1)</sup>	V <sub>IL</sub>	V <sub>ID</sub>	V <sub>IL</sub> Pulse	A9 = V <sub>ID</sub> , A12-A20 Block Address Others = X	Х
Chip Unprotect V <sub>ID</sub> V <sub>ID</sub> V <sub>IL</sub> Pu		VIL Pulse	$\begin{array}{l} A9 = V_{ID}, \ A12 = V_{IH}, \ A15 = V_{IH} \\ Others = X \end{array}$	х	
Block (Group) Protection Verify			$\begin{array}{l} \text{A0} = \text{V}_{\text{IL}}, \text{A1} = \text{V}_{\text{IH}}, \text{A6} = \text{V}_{\text{IL}}, \text{A9} = \text{V}_{\text{ID}}, \\ \text{A12-A20 Block Address} \\ \text{Others} = \text{X} \end{array}$	Pass = XX01h Retry = XX00h	
Block (Group) Unprotection Verify	VIL	V <sub>IL</sub>	V <sub>IH</sub>	$\begin{array}{l} \text{A0} = \text{V}_{\text{IL}}, \text{A1} = \text{V}_{\text{IH}}, \text{A6} = \text{V}_{\text{IH}}, \text{A9} = \text{V}_{\text{ID}}, \\ \text{A12-A20 Block Address} \\ \text{Others} = \text{X} \end{array}$	Retry = XX01h Pass = XX00h

#### Table 32. Programmer Technique Bus Operations, $\overline{\text{BYTE}} = V_{\text{IH}}$ or $V_{\text{IL}}$

Note: 1. Block Protection Groups are shown in APPENDIX A., Tables 23 and 24.

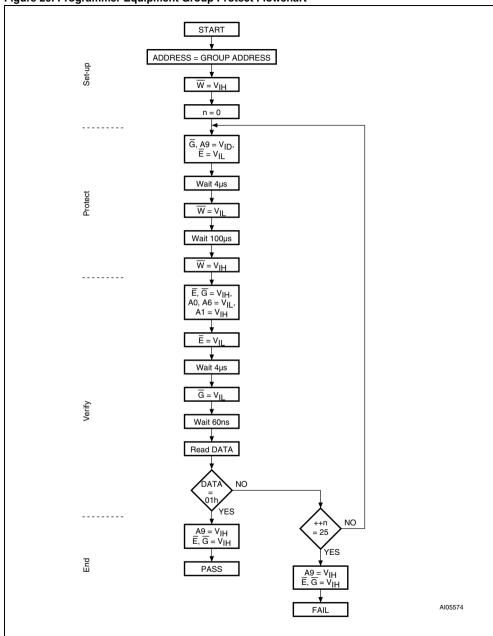
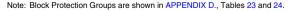
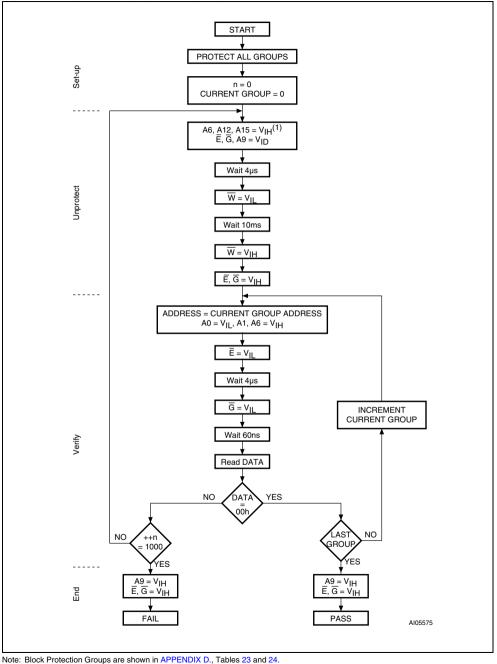


Figure 20. Programmer Equipment Group Protect Flowchart



### Figure 21. Programmer Equipment Chip Unprotect Flowchart





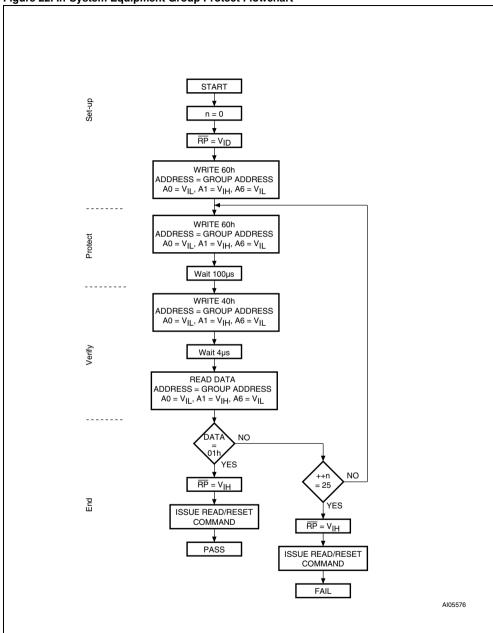
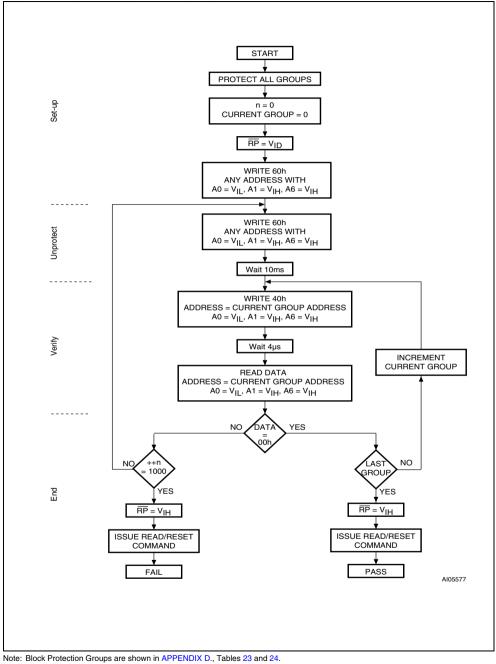


Figure 22. In-System Equipment Group Protect Flowchart

Note: 1. Block Protection Groups are shown in APPENDIX D., Tables 23 and 24.

2. RP can be either at V<sub>IH</sub> or at V<sub>ID</sub> when using the In-System Technique to protect the Extended Block.

### Figure 23. In-System Equipment Chip Unprotect Flowchart



## **REVISION HISTORY**

Table 33	. Document	Revision	History
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Date	Version	Revision Details
20-Sep-2001	-01	First Issue (Target Specification)
26-Oct-2001	-02	Document expanded to full Product Preview
16-Jan-2002	-03	Corrections made in "Primary Algorithm-Specific Extended Query" Table in Appendix-B
19-Apr-2002	-04	Description of Ready/Busy signal clarified (and Figure 16. modified) Clarified allowable commands during block erase Clarified the mode the device returns to in the CFI Read Query command section tPLYH (time to reset device) re-specified.
24-Apr-2002	-05	Values for addresses 23h and 25h corrected in CFI Query System Interface Information table in Appendix B
19-Jul-2002	-06	When in Extended Block mode, the block at the boot block address can be used as OTP. Data Toggle Flow chart corrected. Document promoted from "Product Preview" to "Preliminary Data".
08-Apr-2003	6.1	Revision numbering modified: a minor revision will be indicated by incrementing the digit after the dot, and a major revision, by incrementing the digit before the dot (revision version 06 equals 6.0). Revision History moved to end of document. TFBGA48, 6 x 8mm, 0.80mm pitch package added. Identification Current I <sub>ID</sub> removed from Table 14., DC Characteristics. Erase Suspend Latency time and Data Retention parameters and notes added to Table 7., Program, Erase Times and Program, Erase Endurance Cycles. APPENDIX C., EXTENDED MEMORY BLOCK, added. Auto Select Command sued to read the Extended Memory Block. Extended Memory Block Verify Code row added to Tables 3 and 4, Bus Operations, BYTE = V <sub>IL</sub> and Bus Operations, BYTE = V <sub>IL</sub> . Bank Address modified in Auto Select Command. Chip Erase Address modified in Table 8., Status Register Bits. V <sub>SS</sub> pin connection to ground clarified. Note added to Table 22., Ordering Information Scheme.
07-May-2003	6.2	Table 20., TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Package Mechanical Data, and Figure 18., TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Bottom View Package Outline, corrected.
25-Jun-2003	7.0	Document promoted from Preliminary Data to full Datasheet status. Packing option added to Table 22., Ordering Information Scheme.
18-Sep-2003	7.1	Status of Ready/Busy signal for Erase Suspend Operation modified in Table 8., Status Register Bits. Figures 14 and 15, Toggle and Alternative Toggle Bits Mechanisms added. Table 18., Toggle and Alternative Toggle Bits AC Characteristics, added. Note 1 of Table 28., Device Geometry Definition, modified
07-Oct-2003	7.2	Figures 14 and 15, Toggle and Alternative Toggle Bits Mechanisms modified and Notes 1 and 2 added. Table 18., Toggle and Alternative Toggle Bits AC Characteristics modified. Figure 8. renamed and flowchart modified; Note added.
07-Nov-2003	7.3	Status of Ready/Busy signal for Program Error, Chip Erase and Block Erase modified in Table 8., Status Register Bits.

Date	Version	Revision Details
19-Dec-2003	7.4	<ul> <li>V<sub>CC</sub> minimum value updated in Table 12., Operating and AC Measurement Conditions.</li> <li>V<sub>PP</sub> and I<sub>PP</sub> test conditions updated in Table 14., DC Characteristics.</li> <li>Architecture option updated in Table 22. Ordering Information Scheme.</li> <li>Block Protect/Unprotect code updated in APPENDIX B., Table 29.</li> <li>Customer Lockable Extended Block mechanism modified in APPENDIX C., Extended Memory Block.</li> <li>APPENDIX D., Block Protection updated: Note 1 added in the In-System Technique section and Note 2 added below Figure 22., In-System Equipment Group Protect Flowchart.</li> </ul>
23-Mar-2004	8.0	Introduction of the STATUS REGISTER chapter clarified.
12-July-2004	9.0	90ns speed class removed from datasheet.
12-Aug-2004	10.0	Section , DUAL OPERATIONS AND MULTIPLE BANK ARCHITECTURE added.
27-Sep-2004	11.0	TFBGA63 package removed.
10-Dec-2004	12.0	Status of Ready/Busy signal for Program Error, Chip Erase and Block Erase modified in Table 8., Status Register Bits.
14-Mar-2005	13.0	RB updated in Table 8., Status Register Bits. Fast Program Commands restructured and updated. Unlock Bypass Command updated.
27-Mar-2008	14.0	Applied Numonyx branding.

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